



Navitas

Let's go **GaNFast**[™]

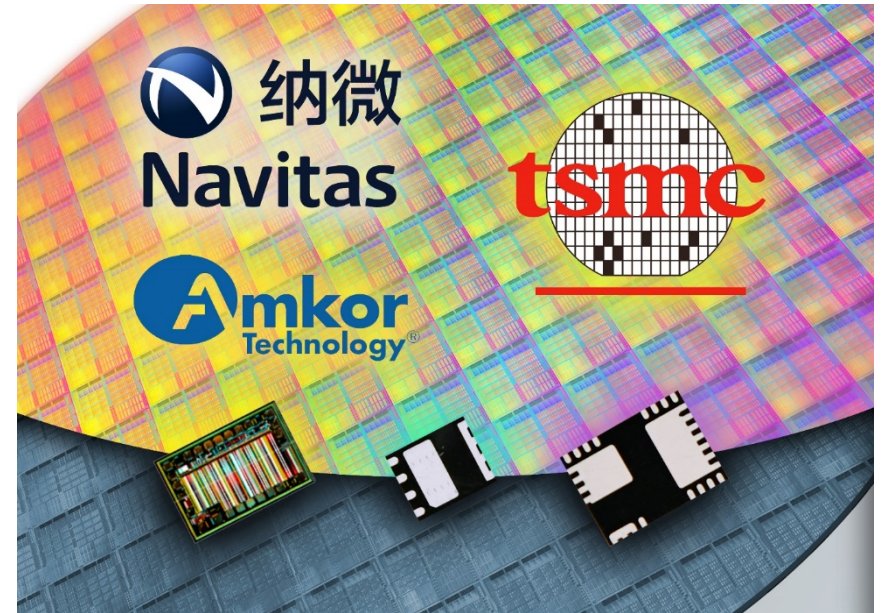
**Monolithic GaN Device Integration Drives Efficiency,
Density and Reliability in Power Conversion**

Dan Kinzer, CTO/COO dan.kinzer@navitasemi.com
& Stephen Oliver, VP Sales & Marketing stephen.oliver@navitassemi.com

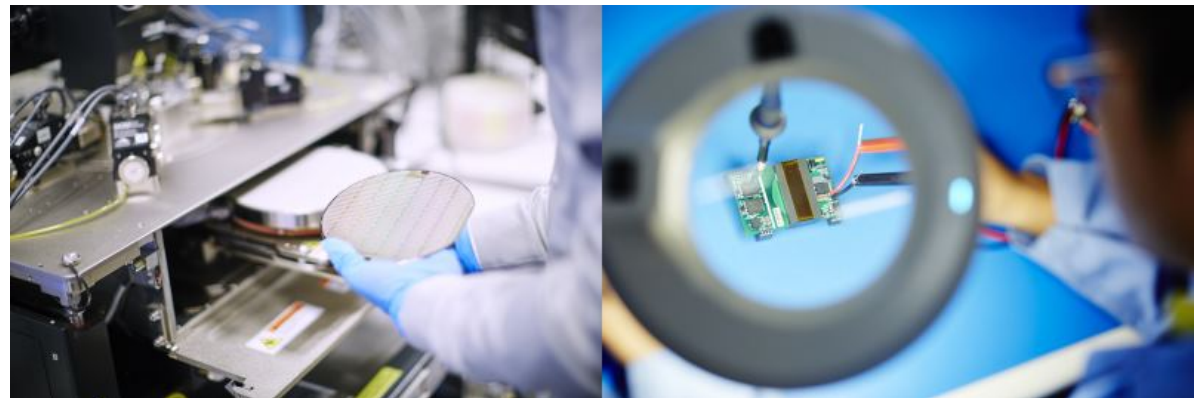
August 16th 2018



- World's first & only GaN power IC company
- Mass production, qualified "Beyond JEDEC"
- Founder member JEDEC JC-70.1 GaN Reliability
- www.navitassemi.com



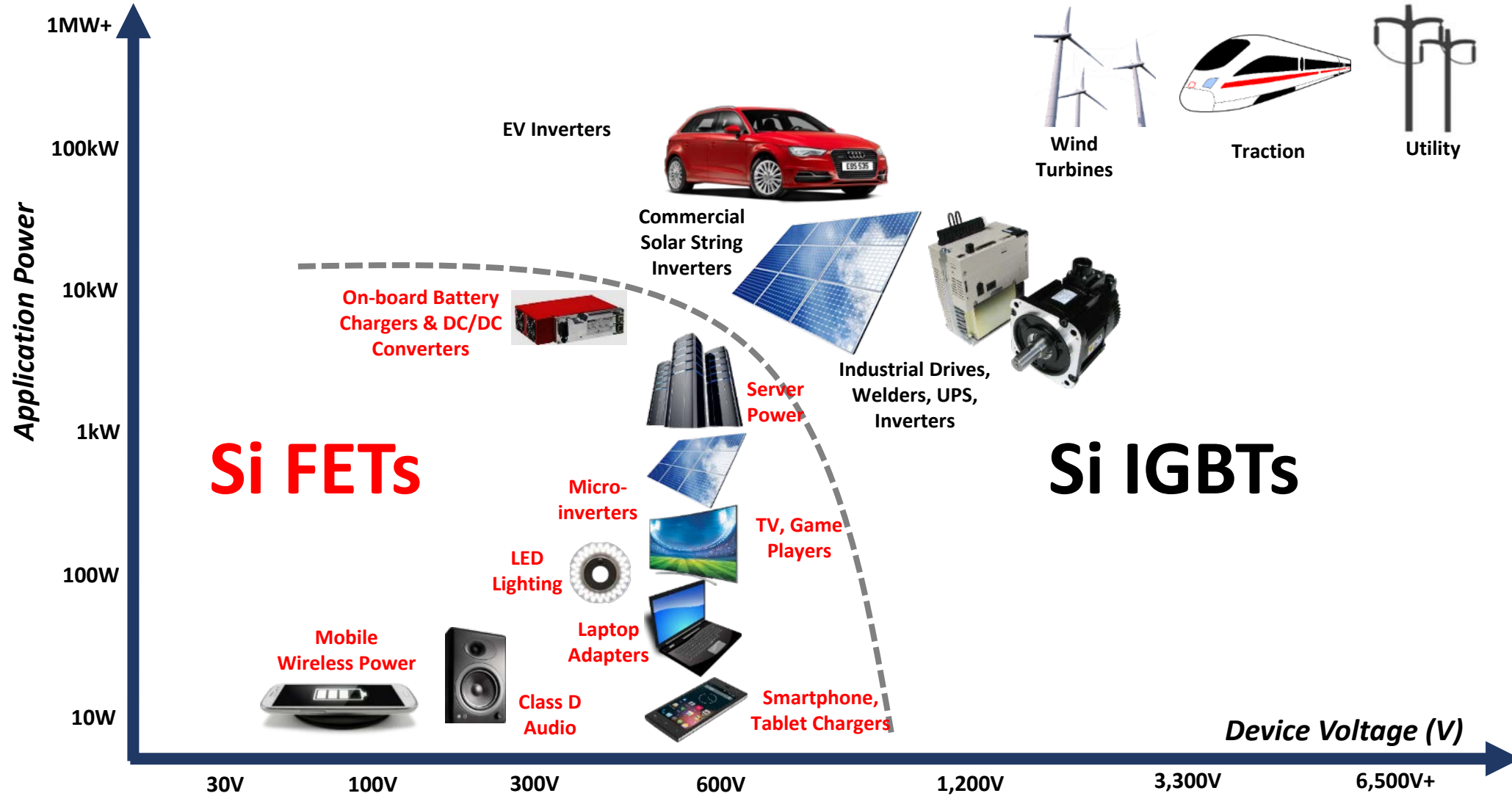
navitas
noun | en·er·gy





The Si Landscape

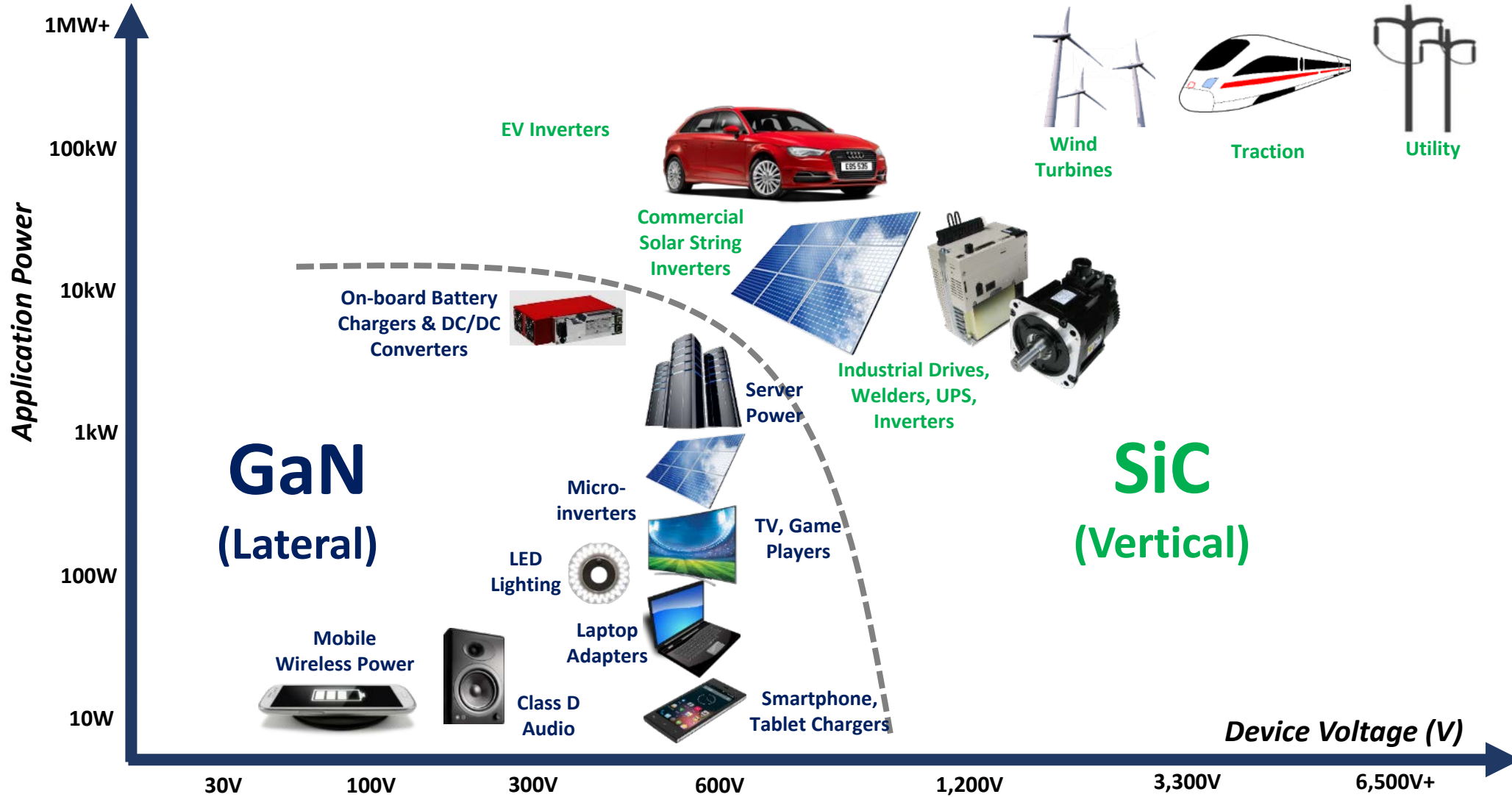
GaNFast™





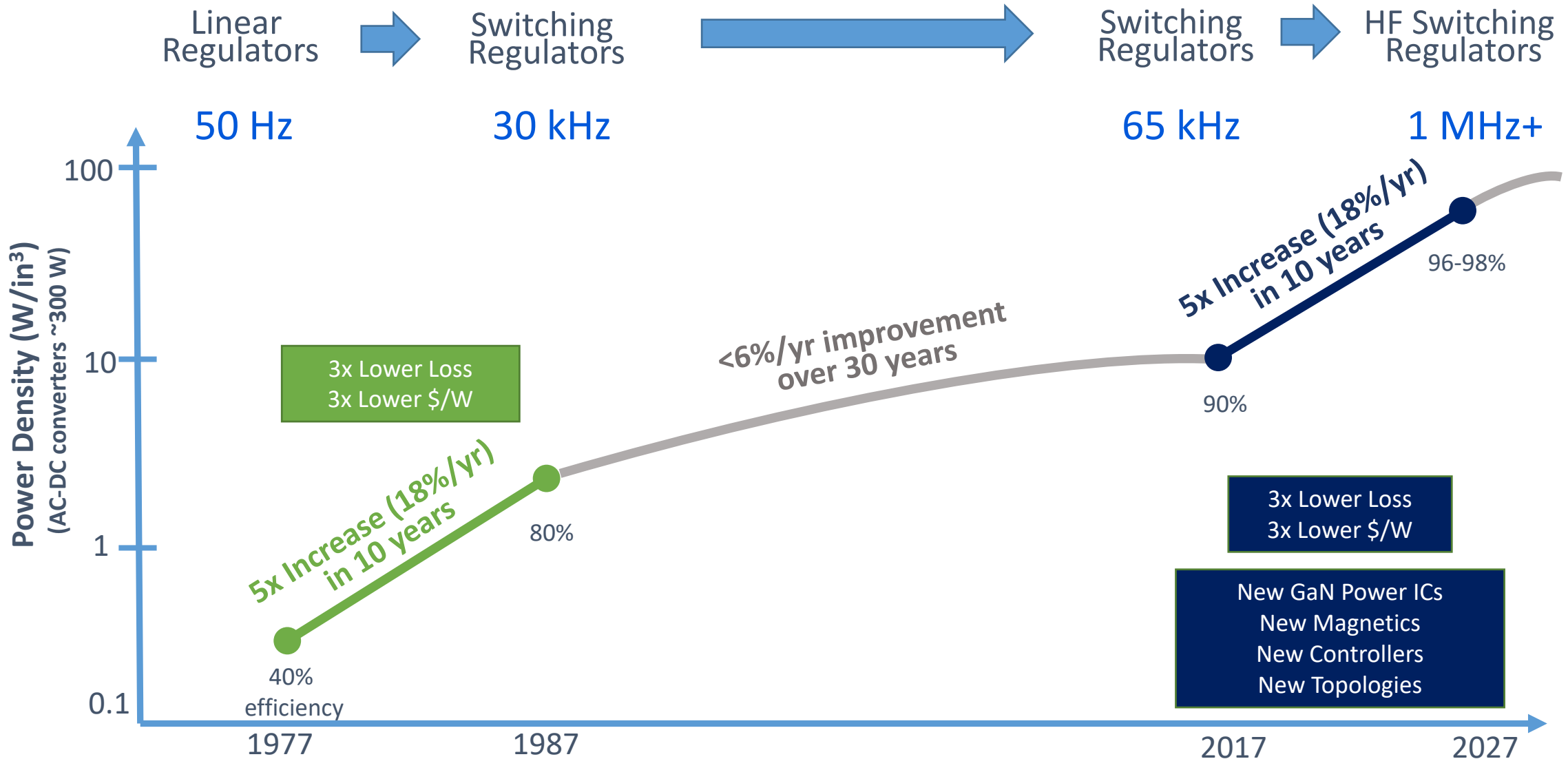
The GaN / SiC Landscape

GaNFast™





The Next Revolution in Power Systems





Market Demands



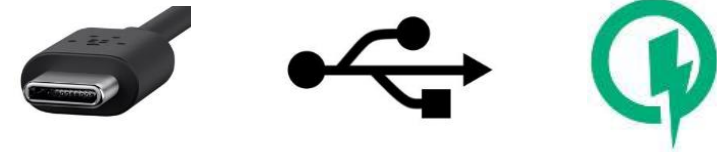
- **Legislative**

- US DoE VI, Euro CoC Tier 2



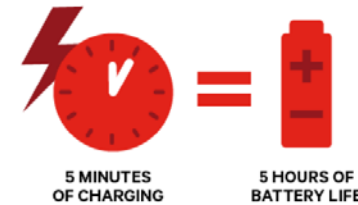
- **Features**

- Type C, USB PD 3.0 / PPS / QC 4.0



- **Performance**

- Fast charging, size, weight, low profile



- **Cost**

- Premium vs old, slow designs?

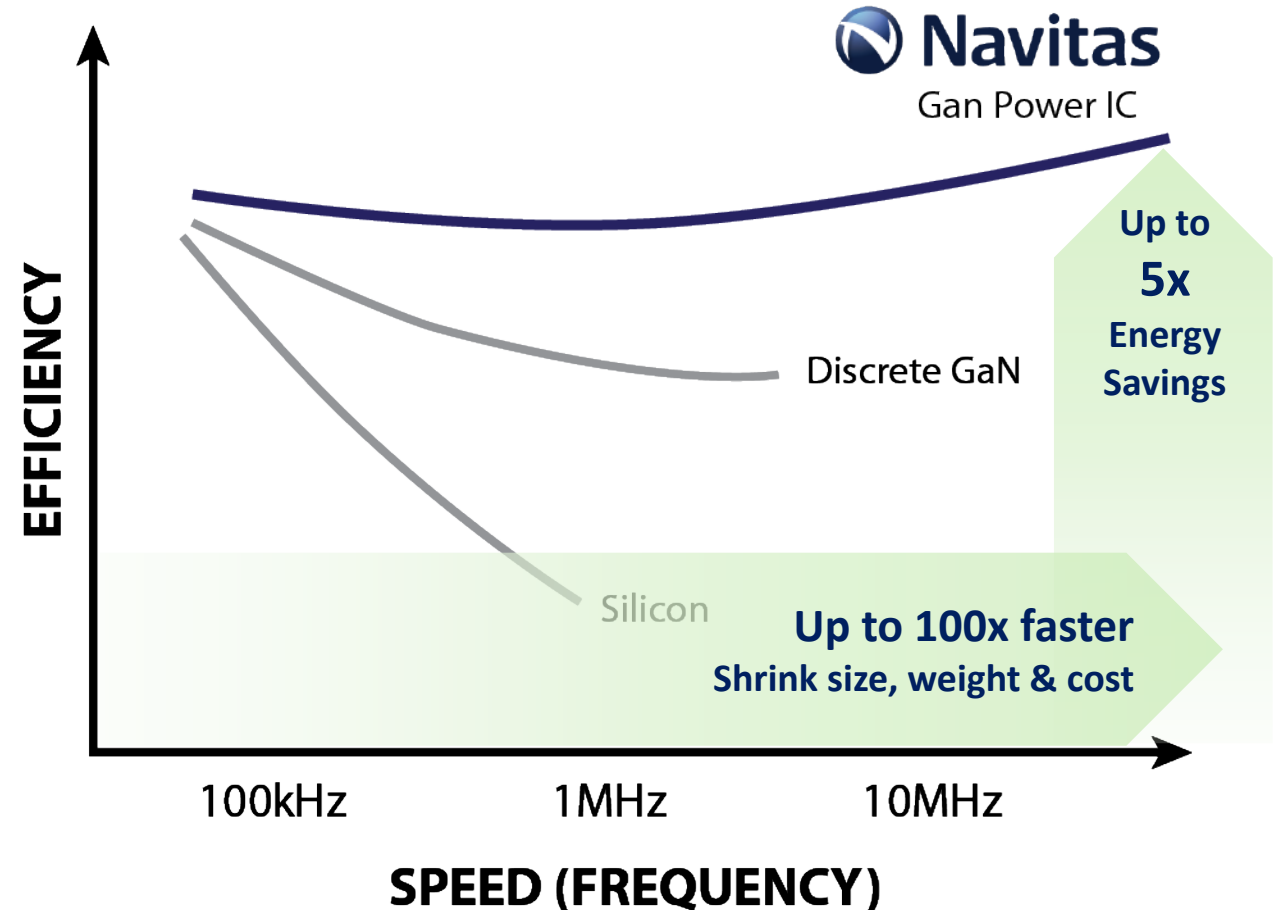




Speed & Efficiency are Key



- **Speed** enables *small size*, *low-cost* and *faster charging*
- **Efficiency** enables *energy savings*
- With Silicon or Discrete GaN power devices, you can get one **or** the other
- With GaN power ICs, you get **both at the same time**, unequaled **Speed & Efficiency**





GaNFast power ICs plus...

- HF Controllers



- HF Magnetics



- HF SR FETs

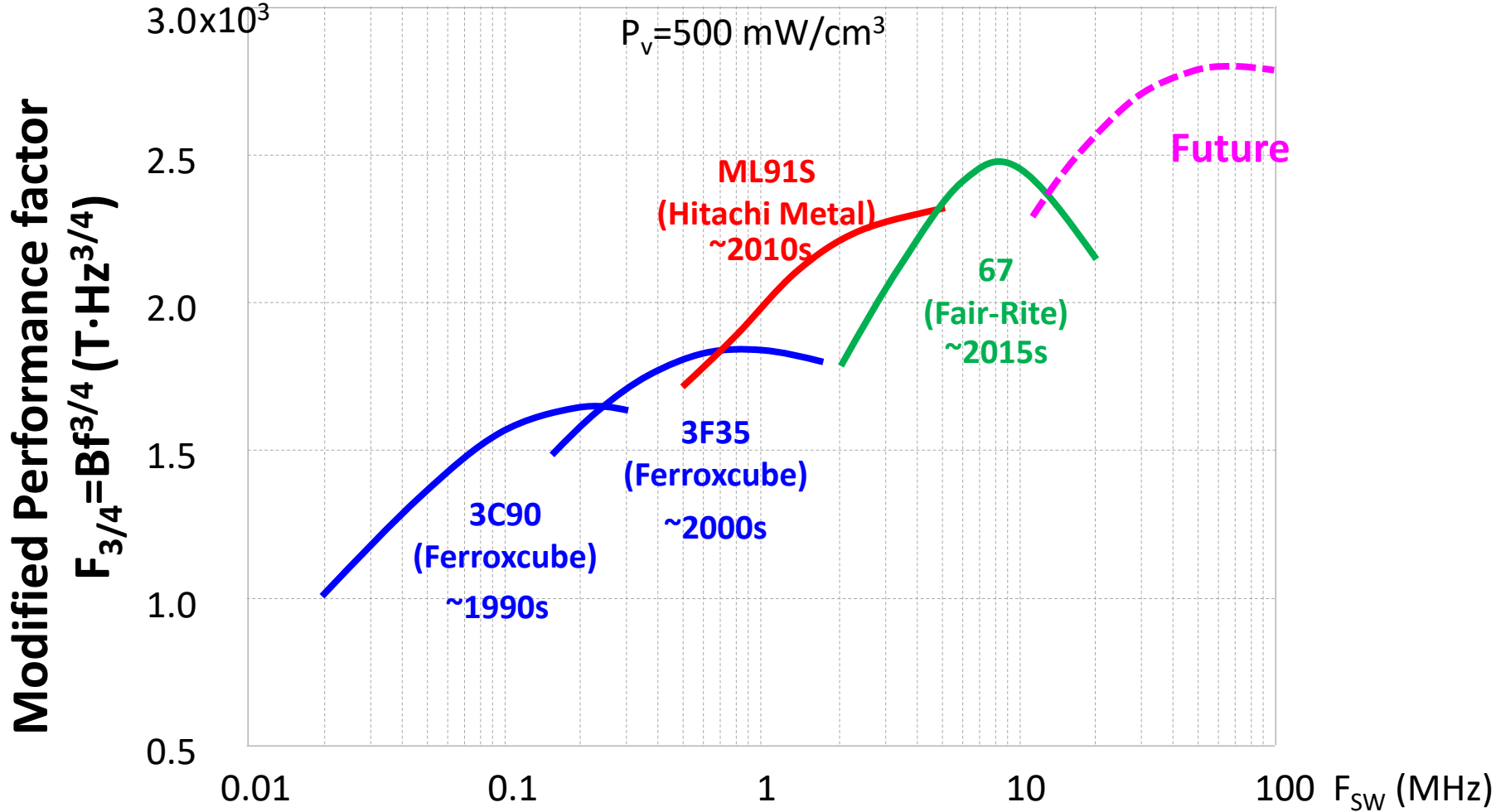


- HF Architectures





Magnetics: 10x Faster Every Decade



Y. Han, G. Cheung, A. Li, C. R. Sullivan and D. J. Perreault, "Evaluation of Magnetic Materials for Very High Frequency Power Applications," in *IEEE Transactions on Power Electronics*, vol. 27, no. 1, pp. 425-435, Jan. 2012.

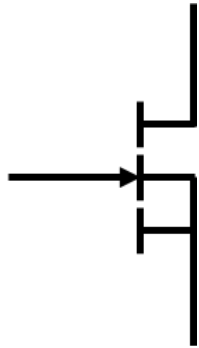
A. J. Hanson, J. A. Belk, S. Lim, C. R. Sullivan and D. J. Perreault, "Measurements and Performance Factor Comparisons of Magnetic Materials at High Frequency," in *IEEE Transactions on Power Electronics*, vol. 31, no. 11, pp. 7909-7925, Nov. 2016.



World's First GaNFast™ Power ICs



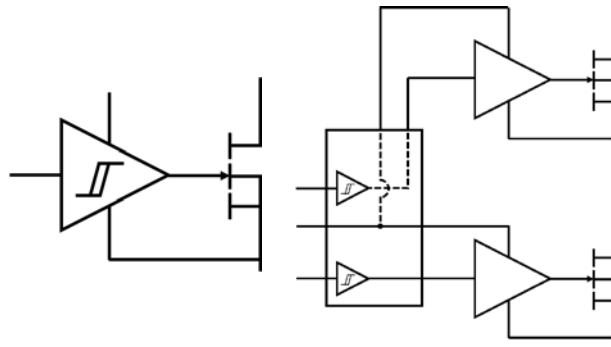
**Fastest, most efficient
GaN Power FETs**



>20x faster than silicon
>5x faster than cascoded GaN
Proprietary design



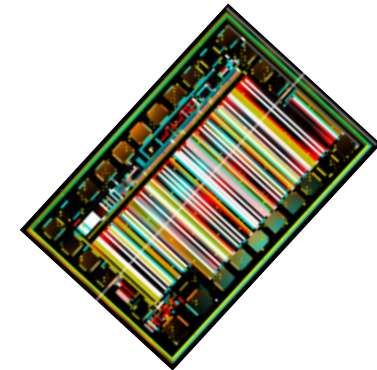
**First & Fastest Integrated
GaN Gate Drivers**



>3x faster than any other gate driver
Proprietary design
30+ patents granted/applied



**World's First
GaNFast™
Power ICs**



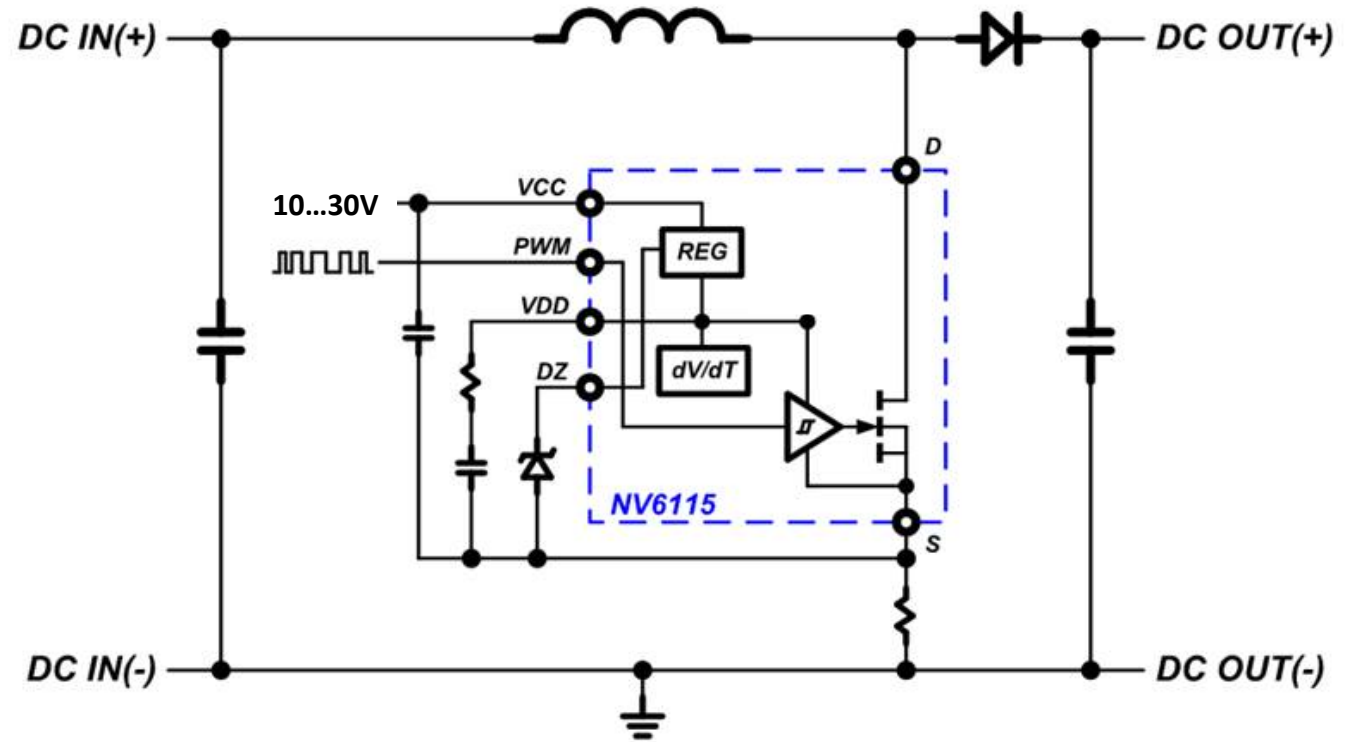
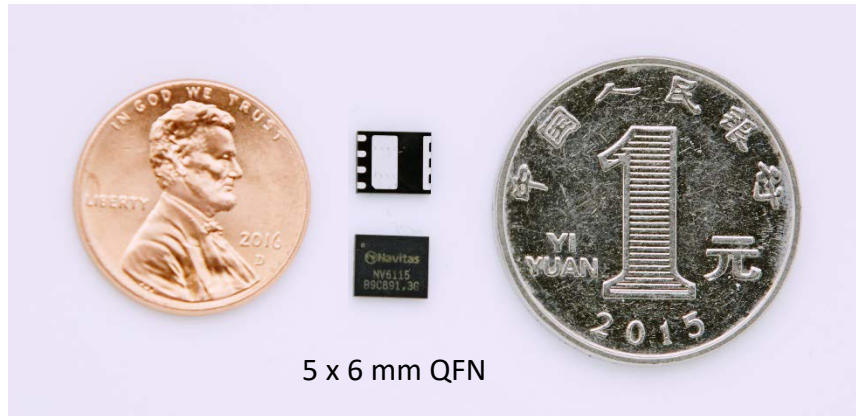
Up to 40MHz switching, 5x higher density & 20% lower system cost



Single GaNFast Power IC



- Monolithic integration, 650V
 - GaN FET
 - GaN Driver
 - GaN Logic
- Mass production



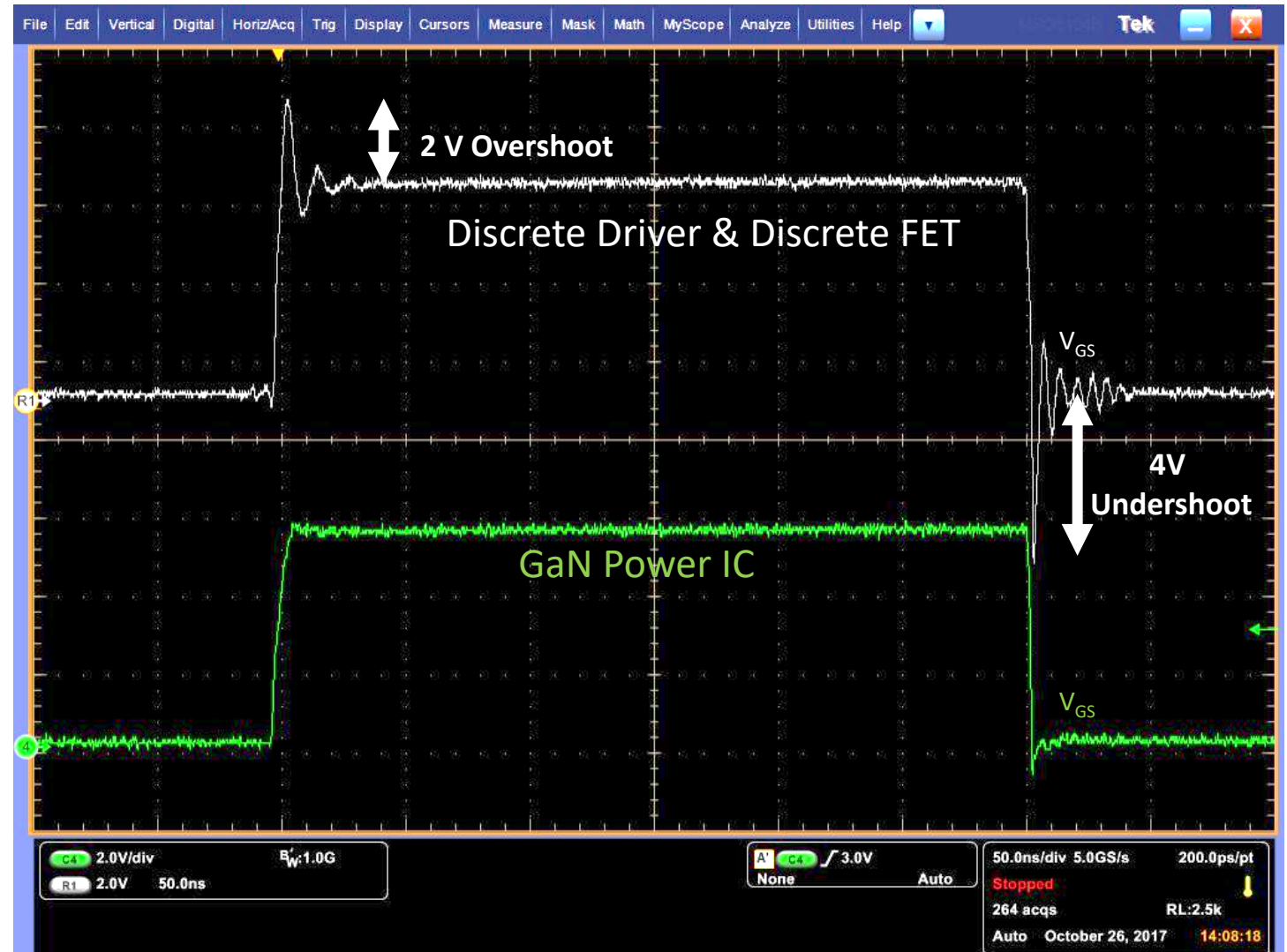


- **Discrete driver**

- Gate-loop inductance creates overshoot (even with good layout)
- Reliability concern

- **GaNFast Power IC**

- No gate loop parasitic
- Clean and fast gate signal
- No CdV/dt turn-on
- No IV crossover turn-off switching losses

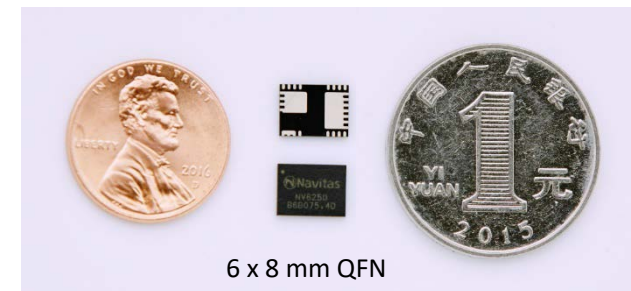
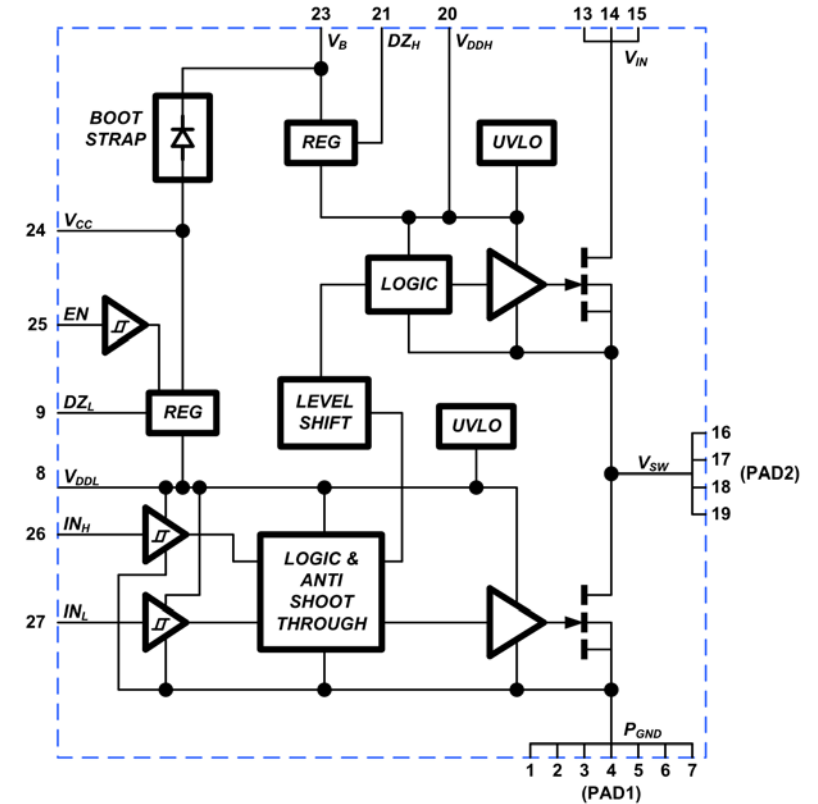
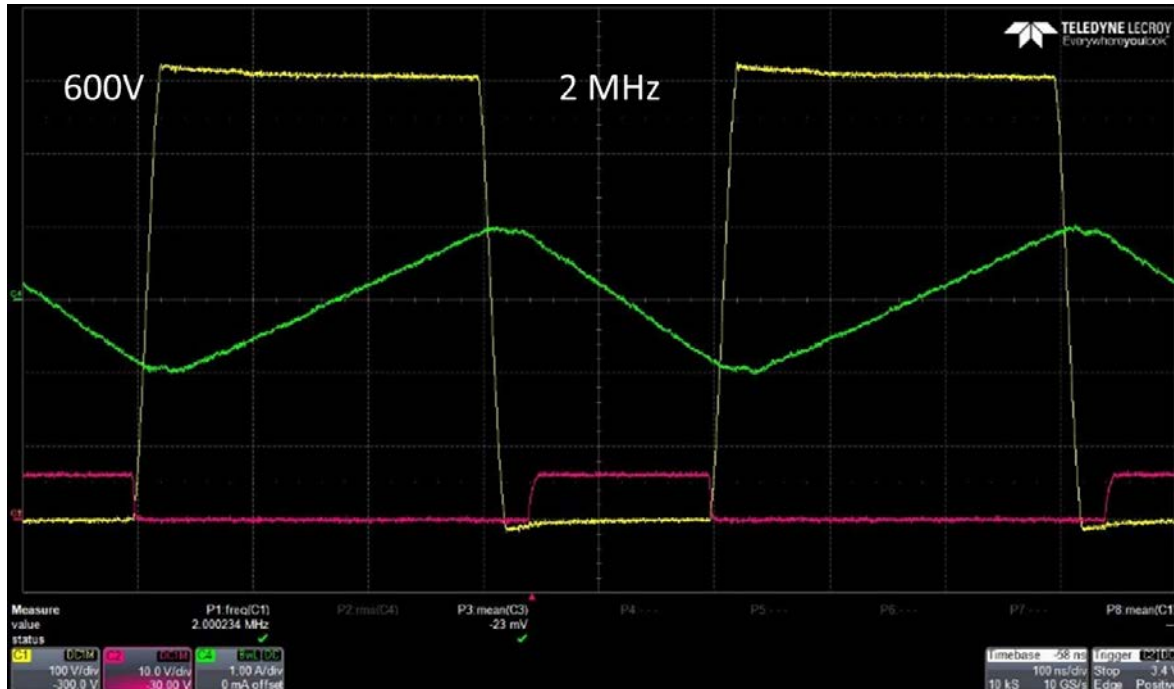




Half-Bridge GaNFast Power IC

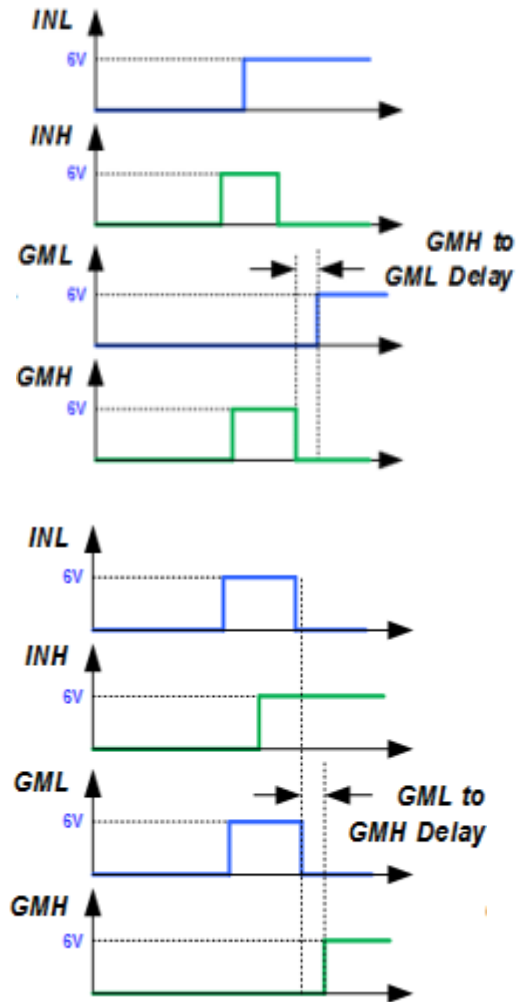


- Monolithic integration, 650V
 - 2x GaN FETs
 - 2x GaN drivers
 - GaN Logic (level-shift, bootstrap, UVLO, shoot-through, ESD)



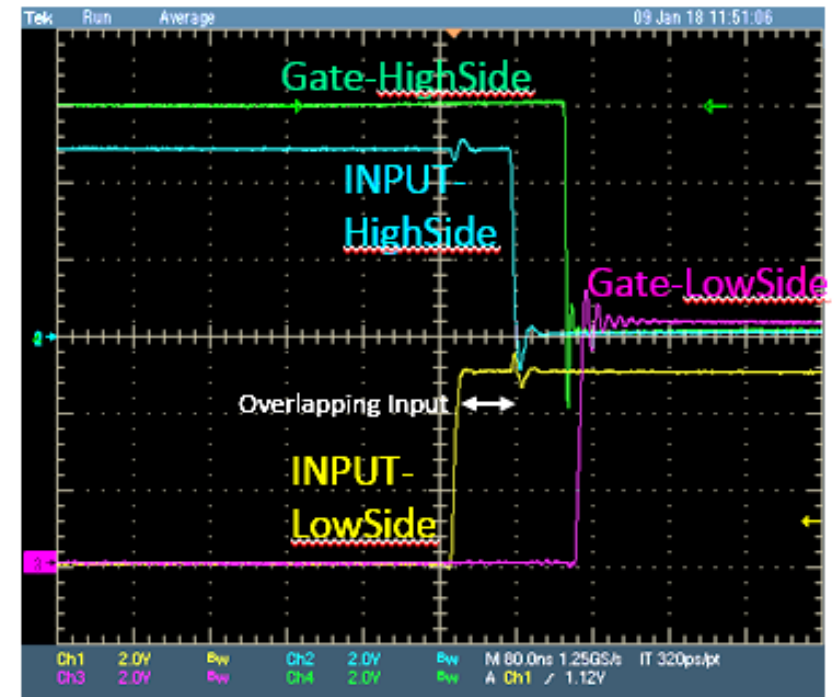
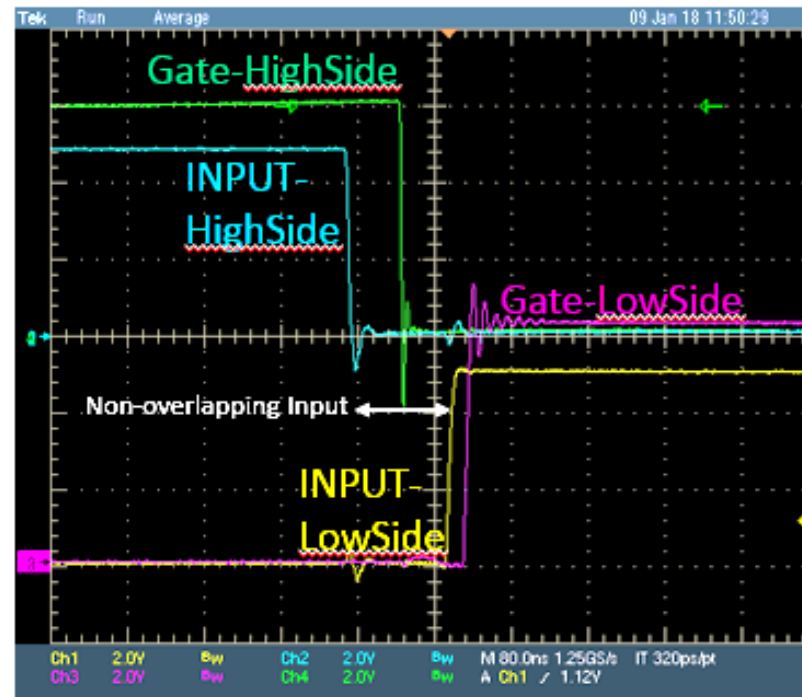


Robust GaNFast Half-Bridge



Non-Overlapping Logic Input
(Typical Operation)

Overlapping Logic Input
(GaNFast Power IC Protection)



5 V digital input, 6.2 V gate output, 80 ns/div

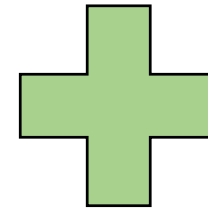


'Beyond' JEDEC Qualification



GaN-Based Qual Plan

	Reference	Test Conditions	Duration	Lots	S.S.
Package Stress	JESD22-A113 J-STD-020	Preconditioning (MSL1): Moisture Preconditioning + 3x reflow: HAST, UHAST, TC & PC	N/A	3	308
	JESD22-A104	Temperature Cycle: -55°C / 150°C	1,000cy	3	77
	JESD22-A122	Power Cycle: Delta Tj = 100°C	10,000cy	3	77
	JESD22-A110	Highly Accelerated Stress Test: 130°C / 85%RH / 100V V _{DS}	96hrs	3	77
Die Stress	JESD22-A108	High Temperature Reverse Bias: 150°C / 520V V _{DS}	1,000hrs	3	77
	JESD22-A108	High Temperature Gate Bias: 150°C / 6V V _{GS}	1,000hrs	3	77
	JESD22-A108	High Temperature Operating Life	1,000hrs	3	77
	JS-001-2014	Human Body Model ESD	N/A	1	3
	JS-002-2014	Charged Device Model ESD	N/A	1	3



Lifetime Models
(HTOL, HTRB)

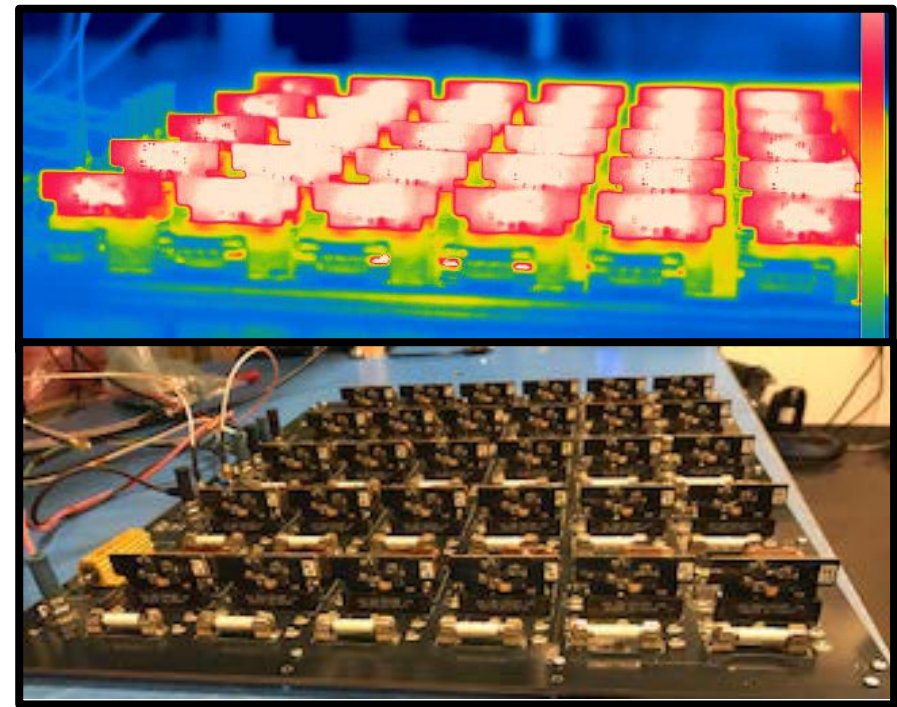
Failure Modes
Established

Application Specific HTOL Test Bench



HTOL Mother Board

- Matches all elements of application profile
 - FET & IC
- Many cells in parallel
 - Statistical sample sizes
- Low total power consumption
- Conditions changeable to develop lifetime and acceleration models



Qualification

3 Lots x 77

Lifetime Models

Voltage
Current
Frequency
Temperature

Early Life Failure Rate

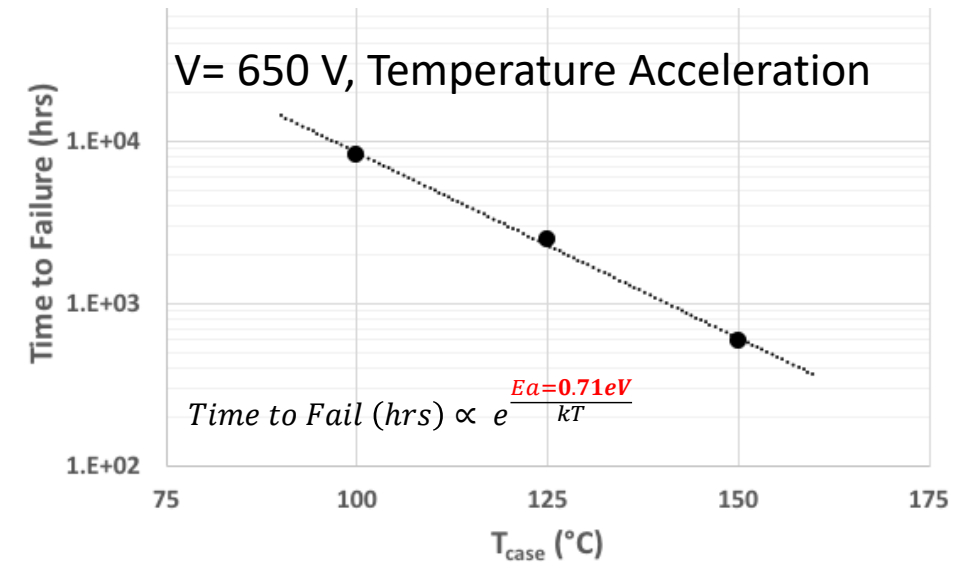
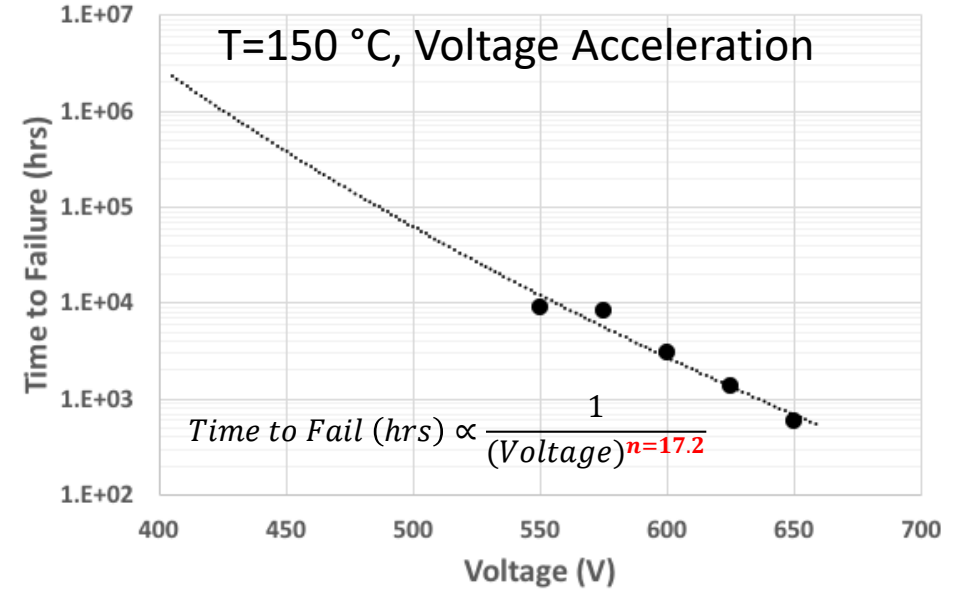
3 Lots x 1,000



HTOL-based Lifetime Model



Voltage/ Temperature	100	125	150
550			✓
575			✓
600			✓
625			✓
650	✓	✓	✓





Lifetime Estimation: ACF Charger



$$\text{Temperature Acceleration Factor (AF}_{\text{temp}}) = e^{\frac{E_a}{k} \times (\frac{1}{T_{\text{application}}} - \frac{1}{T_{\text{reliability}}})}$$

$E_a = 0.71\text{eV}$

$$\text{Voltage Acceleration Factor (AF}_{\text{voltage}}) = (\frac{V_{\text{reliability}}}{V_{\text{application}}})^n$$

$n = 17.2$

$$\text{Total Acceleration Factor (AF}_{\text{Total}}) = \text{AF}_{\text{TEMP}} \times \text{AF}_{\text{VOLTAGE}}$$

$$\text{Lifetime estimate in application} = \text{AF}_{\text{Total}} \times \text{Time to failure in reliability (TTF}_{\text{reliability}})$$

ACF Charger
Full-Power
Profile →

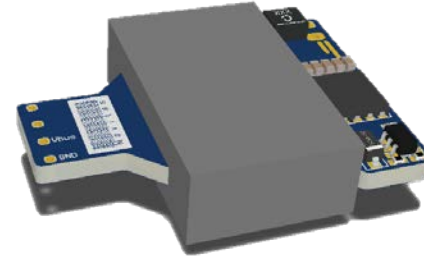
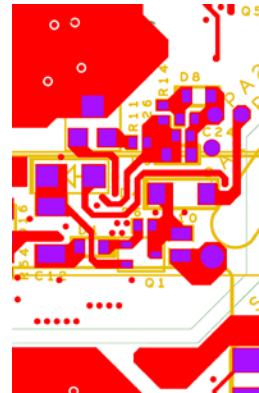
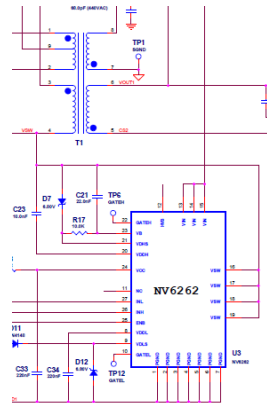
AC line Voltage (V)	Rectified AC voltage (V)	Reflected Voltage (V)	Switch Voltage (V)	Full power Temp (°C)
120	170	120	290	85
240	340	120	460	85

$$\text{Lifetime} = \text{AF}_{\text{Total}} \times \text{TTF}_{\text{reliability}} = \mathbf{233 \text{ years}} @ 240\text{V AC input}$$

Predicted lifetime in charger application (ACF) exceeds 10yr lifetime requirement



GaNFast Applications

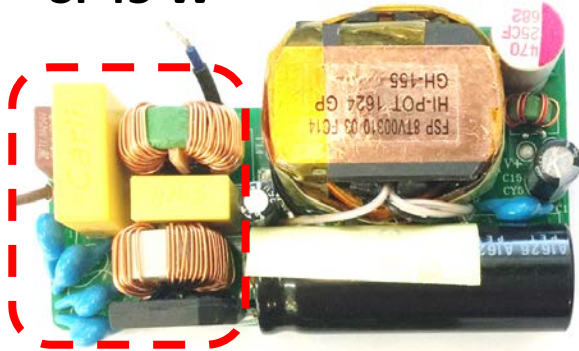




EMI? Si QR @65 kHz vs. GaN ACF @300 kHz



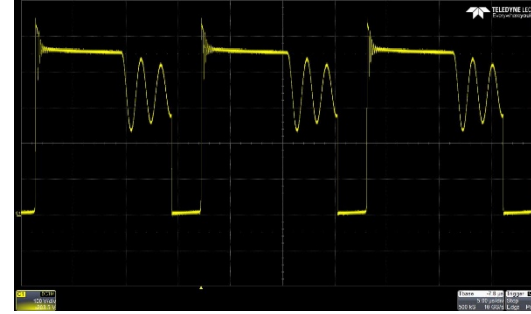
Si 45 W



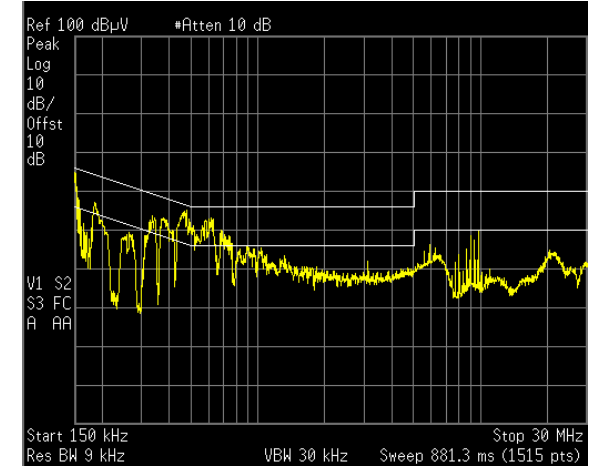
90V_{AC}



240V_{AC}

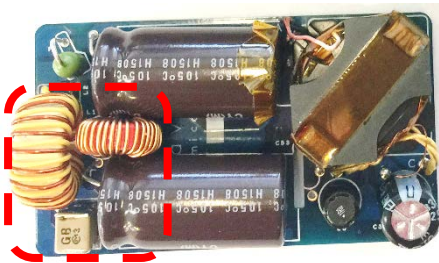


115V_{AC}

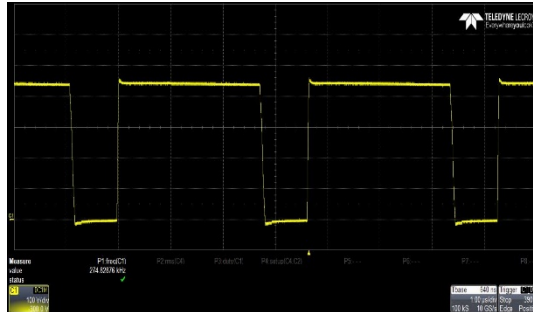


Si: Overshoot/ringing: Need low-frequency to pass EMI

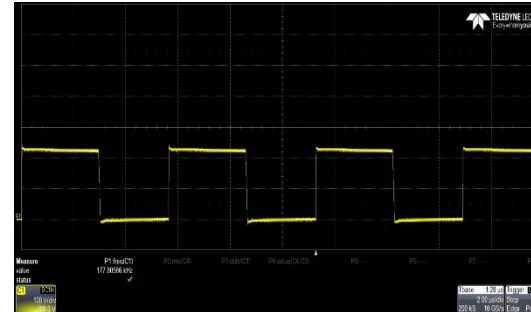
GaNFast 45 W



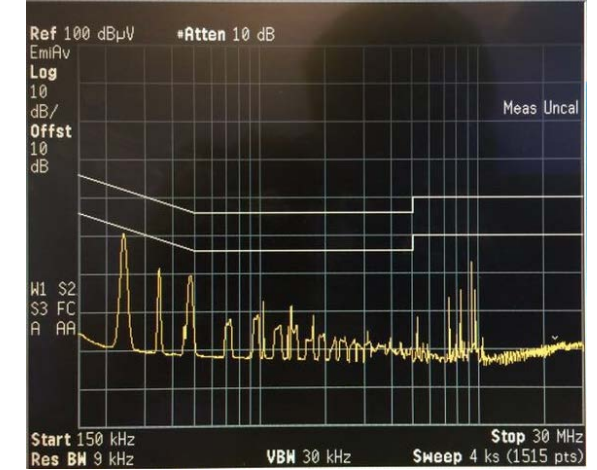
90V_{AC}



240V_{AC}



115V_{AC}



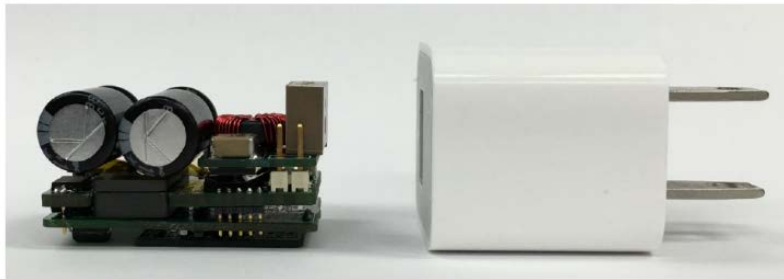
**GaN: No overshoot/ringing: good EMI
Smaller, cheaper EMI filter**



Quiet Power: GaNFast ACF at 1 MHz



- High frequency + Soft-switching + Pre-emptive EMI design



CPES Prototype
25W

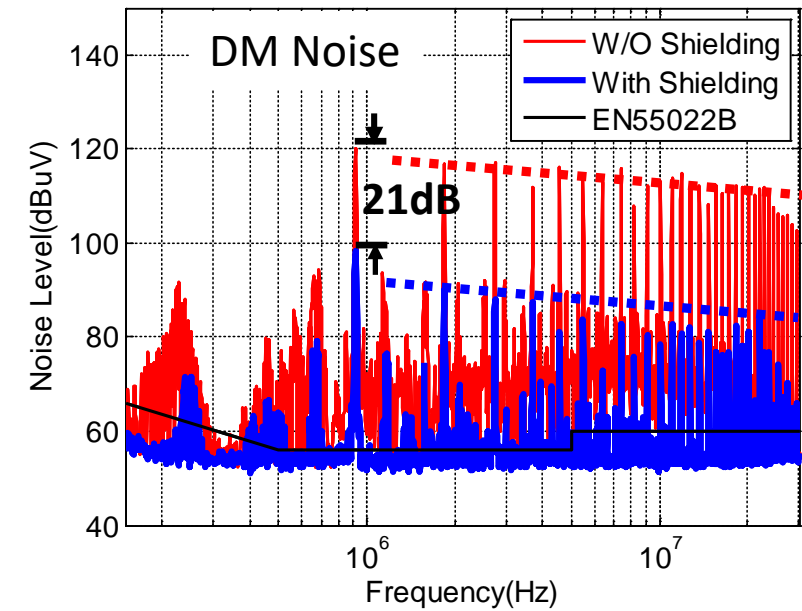
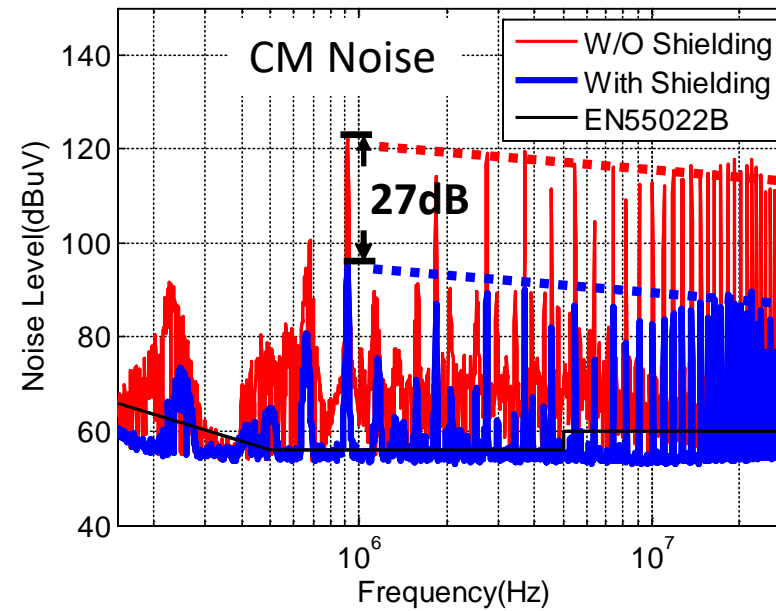
iPhone charger
5W

Conducted EMI Analysis and Filter Design for MHz Active Clamp Flyback Front-end Converter

Xiucheng Huang, Junjie Feng, Fred C. Lee, Qiang Li, and Yuchen Yang
Center for Power Electronics Systems, the Bradley Department of Electrical and Computer Engineering
Virginia Polytechnic Institute and State University, Blacksburg, VA, 24061, USA

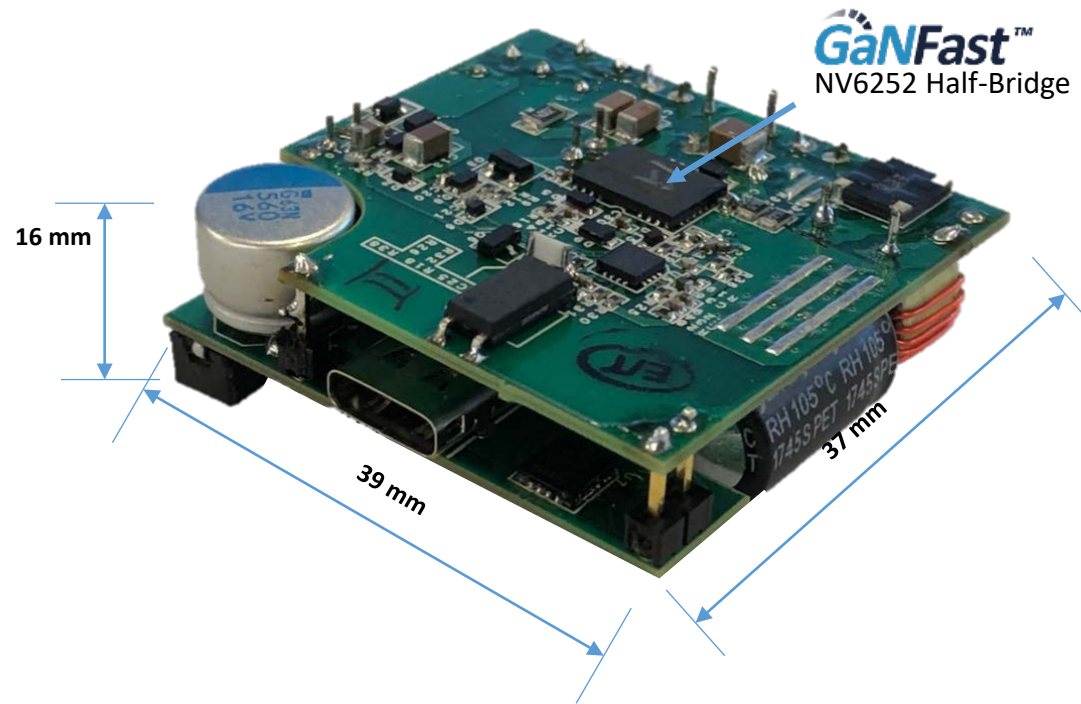
978-1-4673-9550-2/16/\$31.00 ©2016 IEEE

1534





World's Smallest 27 W USB-PD

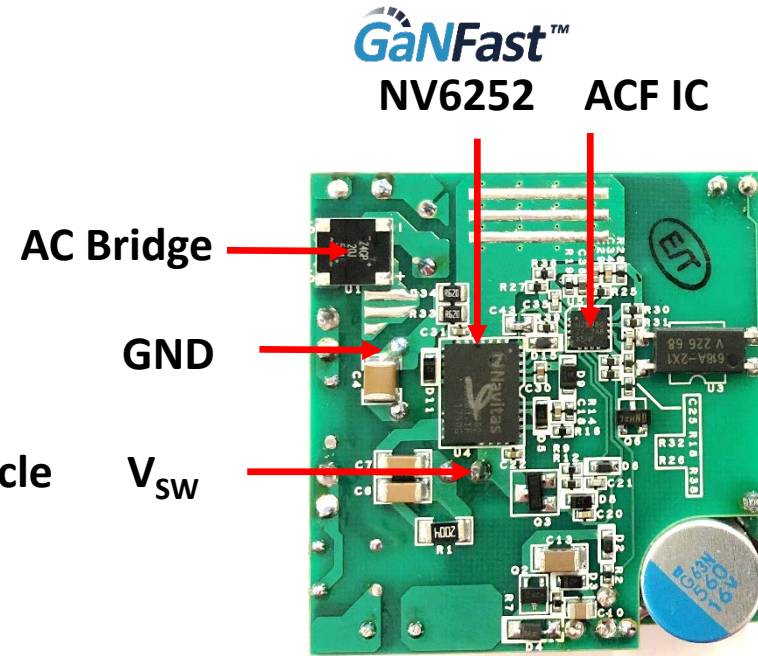
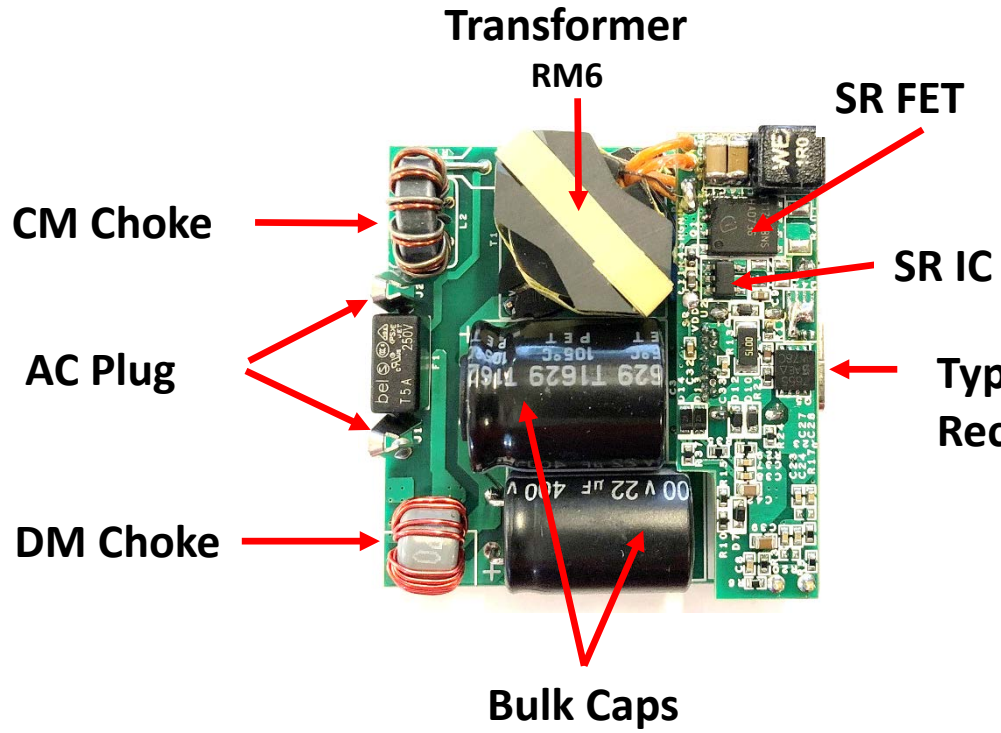


Power, Output	27 W USB-PD
Topology	ACF with UCC28780 and NV6252 GaNFast Power IC
Frequency	300 kHz
Size	23 cc (39 cc with case)
Density	1.2 W/cc (19 W/in ³) (0.7 W/cc (11 W/in ³) cased)
Efficiency	>93% peak, 92.8% at 90 V _{AC} , full load DoE Level VI, Euro CoC (EuP) Tier 2

Available now

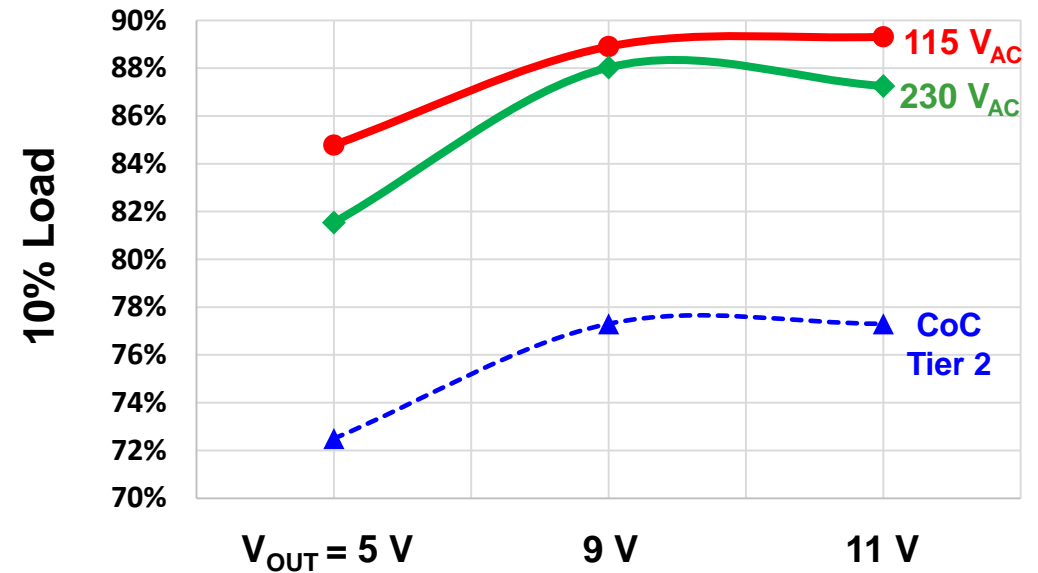
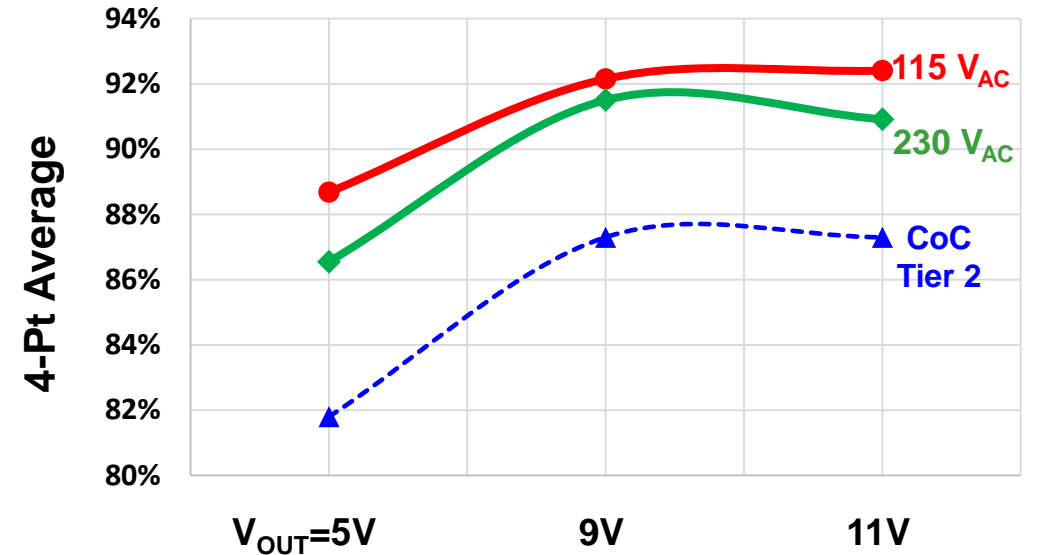
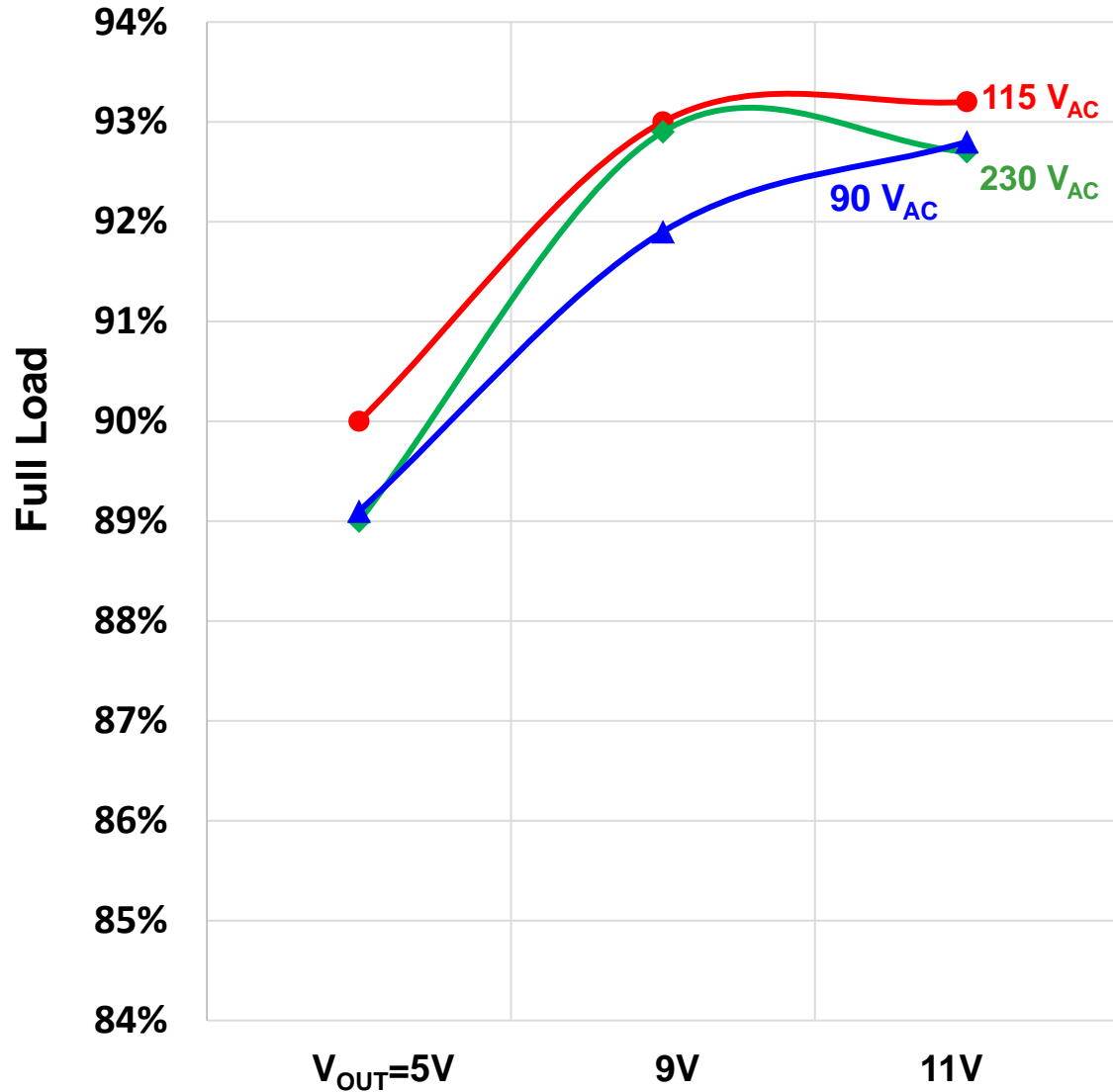


27 W Clean Design





27 W High Efficiency

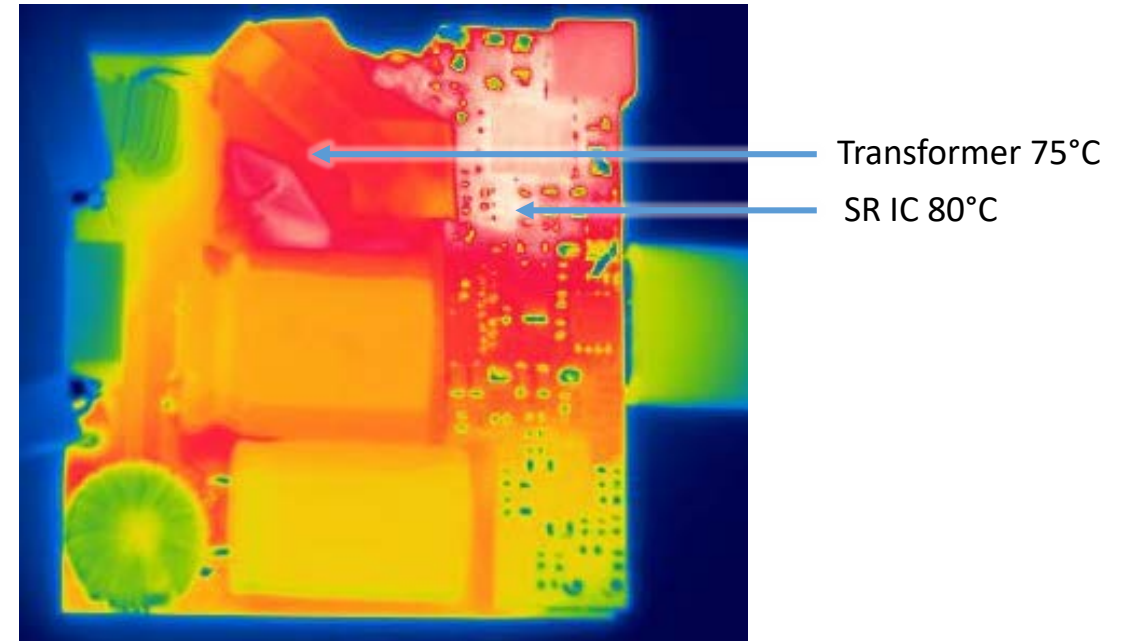
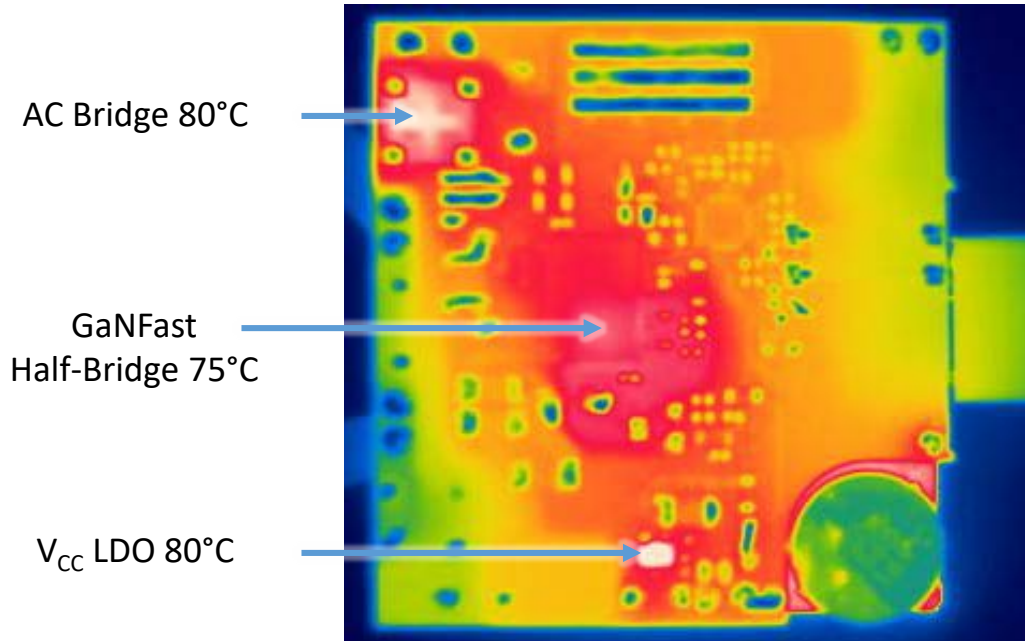




27 W Cool Operation

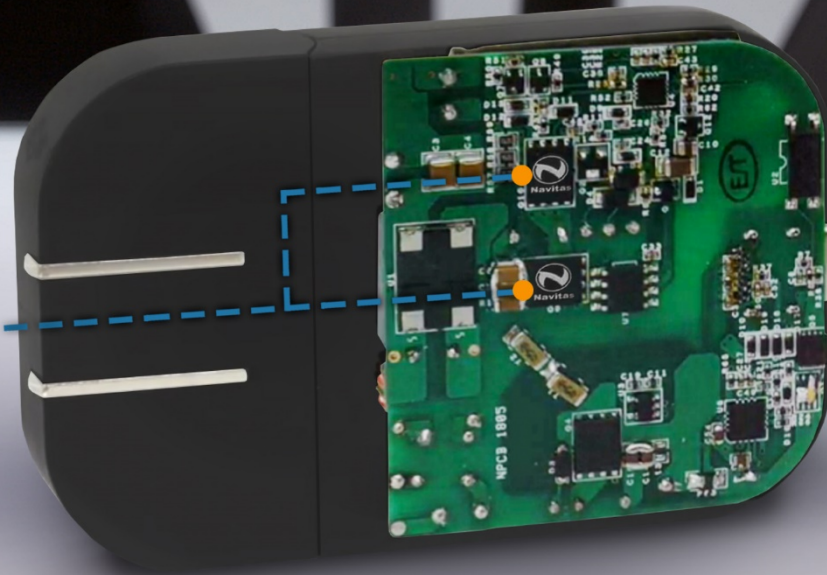
Top

Bottom



90 V_{AC}, 27 W, 25 °C, uncased, no airflow

GaNFast™
GaN Power IC

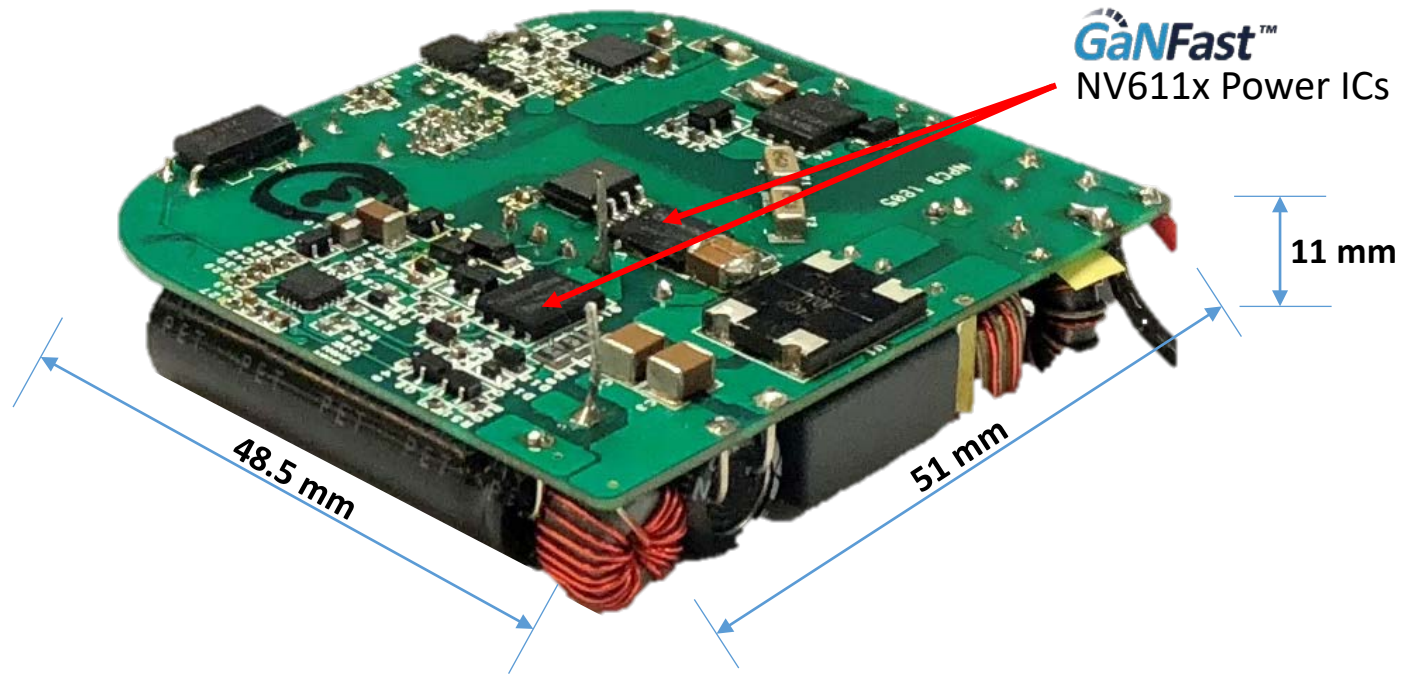


 **Navitas**

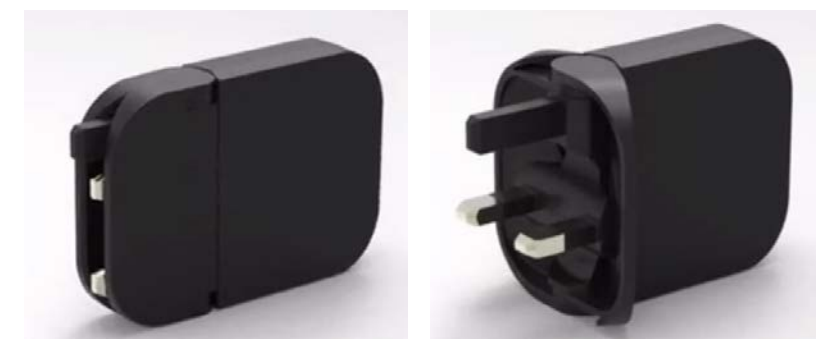
mu² one



World's Thinnest Universal 45 W

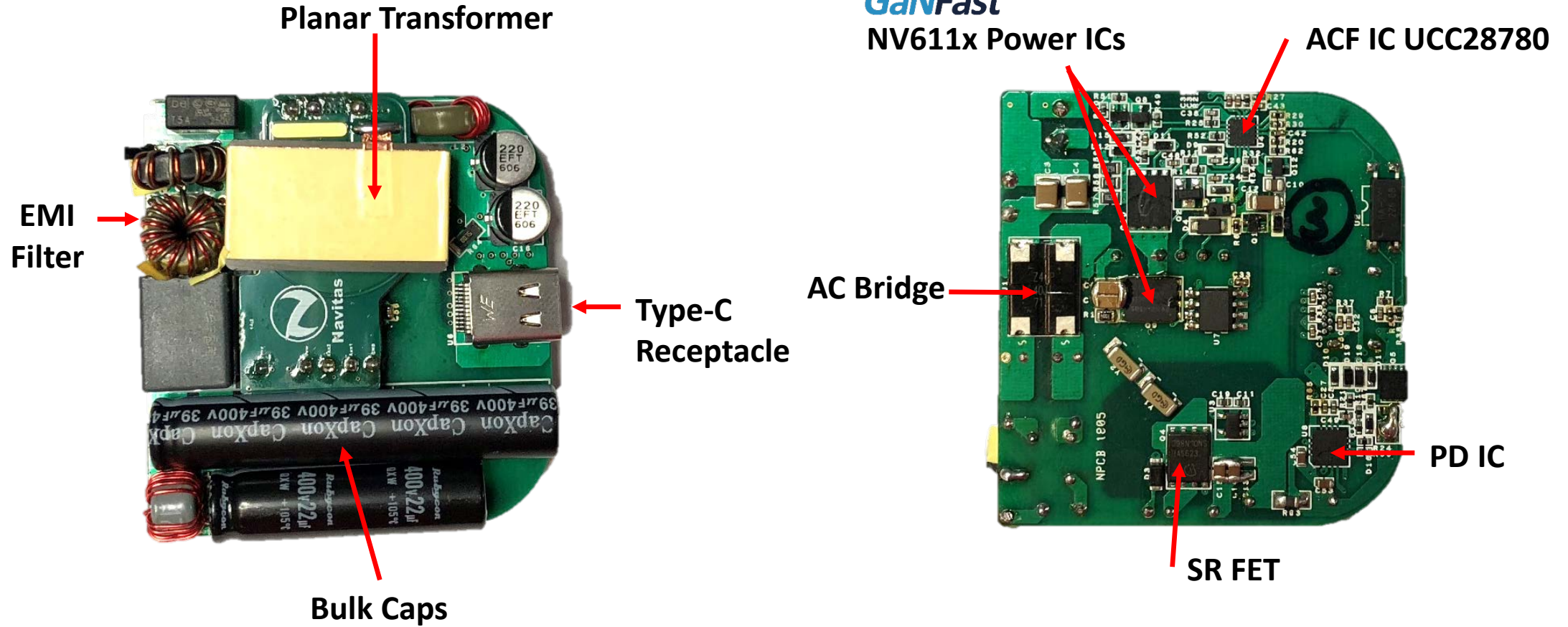


- In mass production, see www.kickstarter.com , search “Mu One”
- Size : 29 cc (41 cc with case)
- Density : 1.7 W/cc (27 W/in³), 1.1 W/cc (18 W/in³) cased





45 W Mu One: Major Components





45 W Mu One: Cool Operation



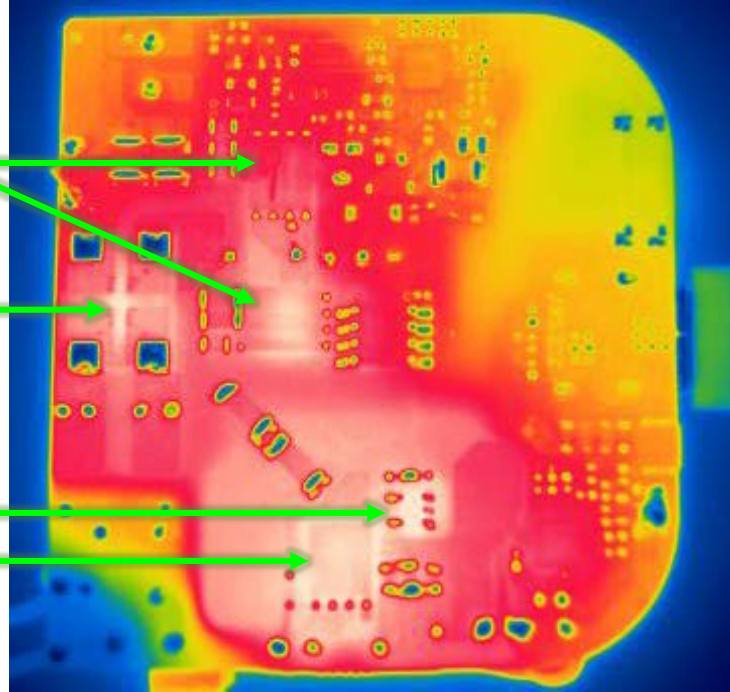
Top

Bottom

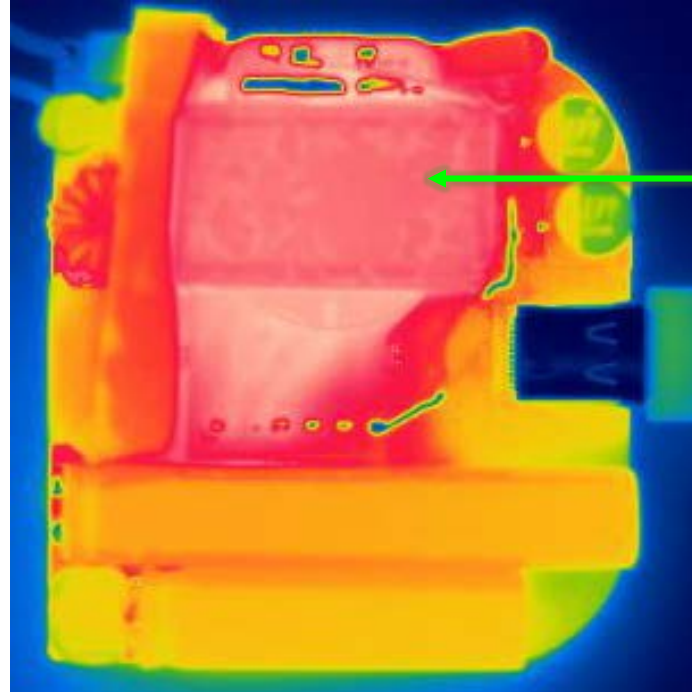
GaNFast
Power IC 75°C, 80°C

AC Bridge 80°C

SR IC 85°C
SR FET 85°C



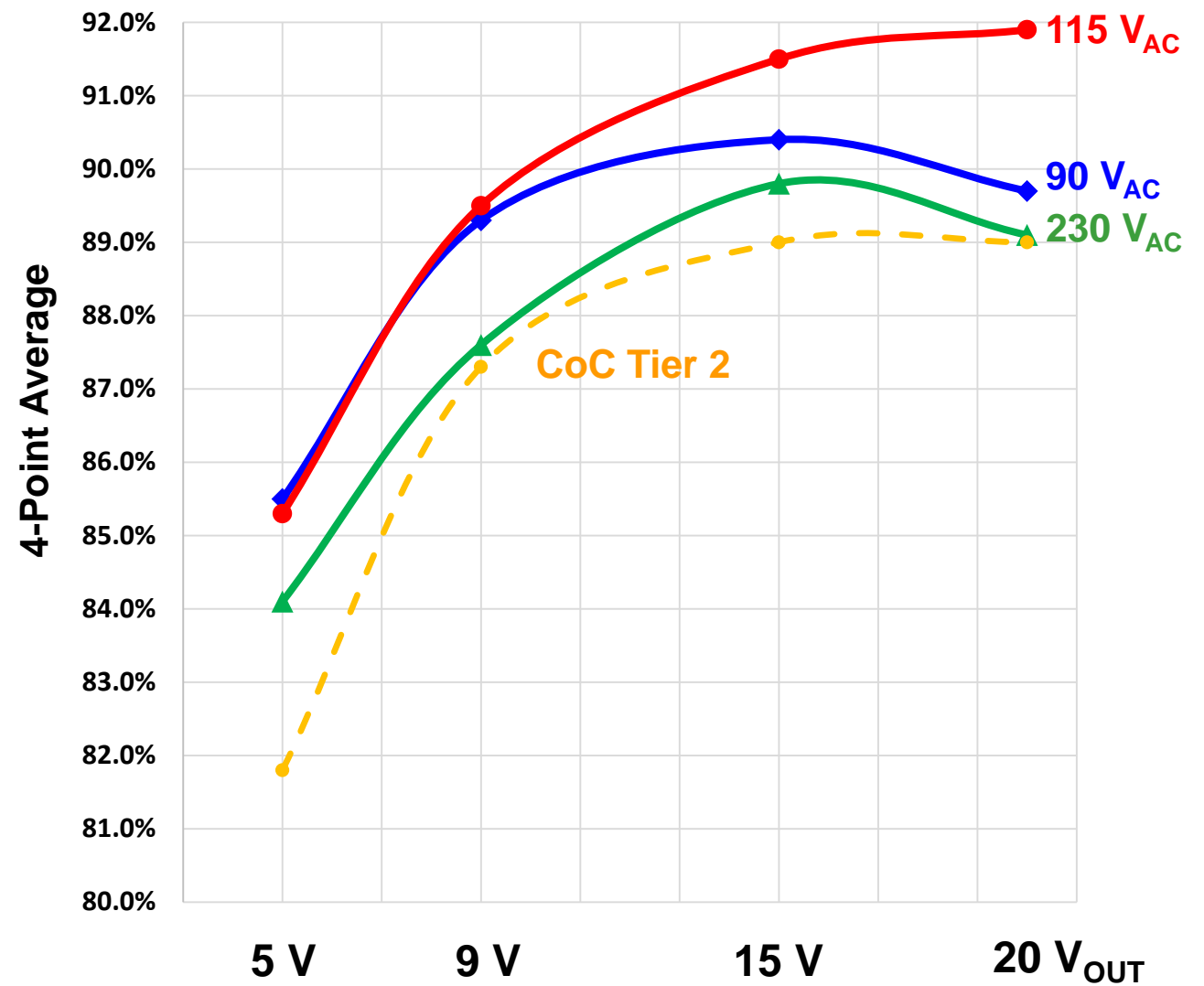
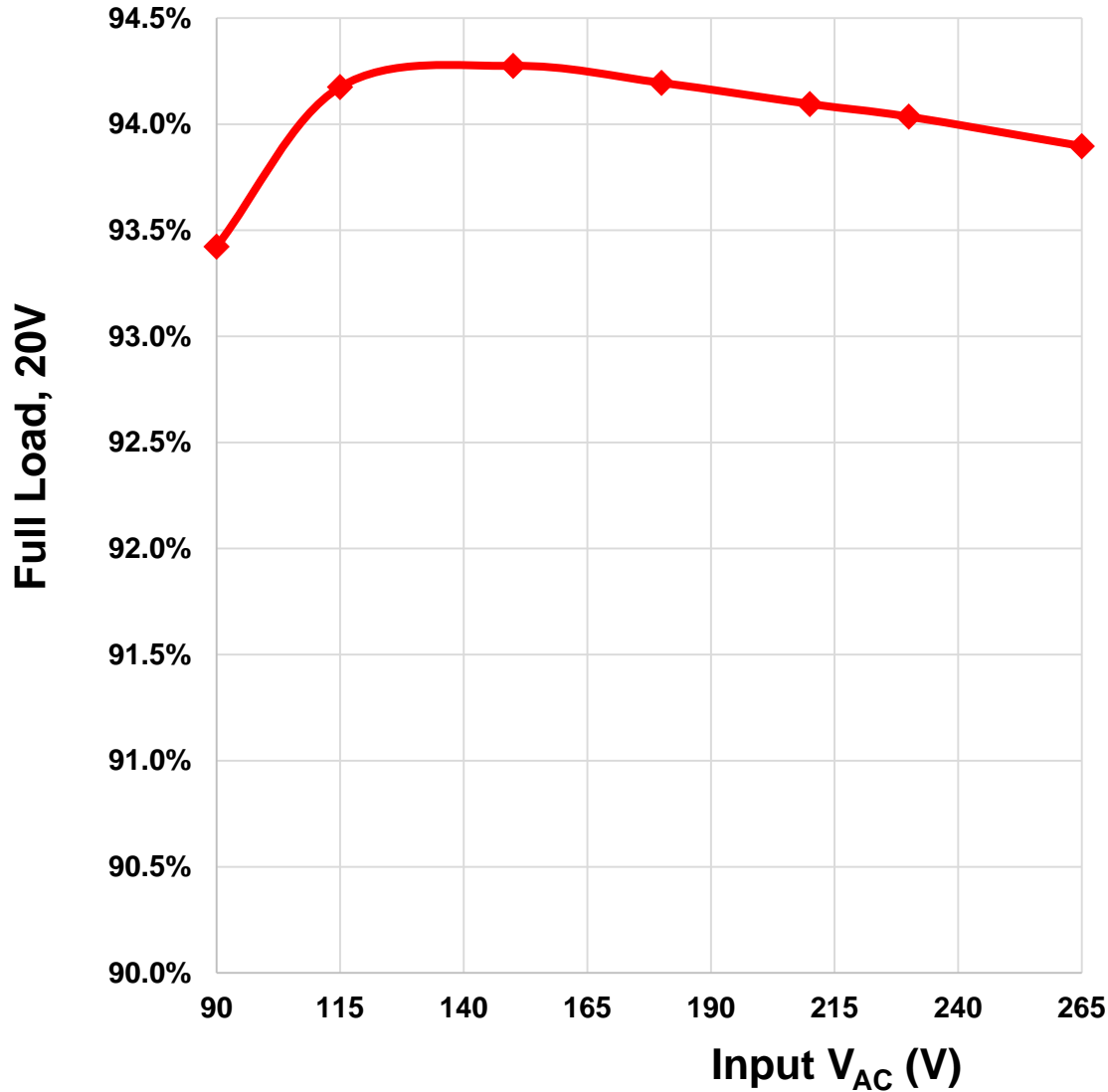
Transformer 80°C



90 V_{AC}, 45 W, 25 °C, uncased, no airflow



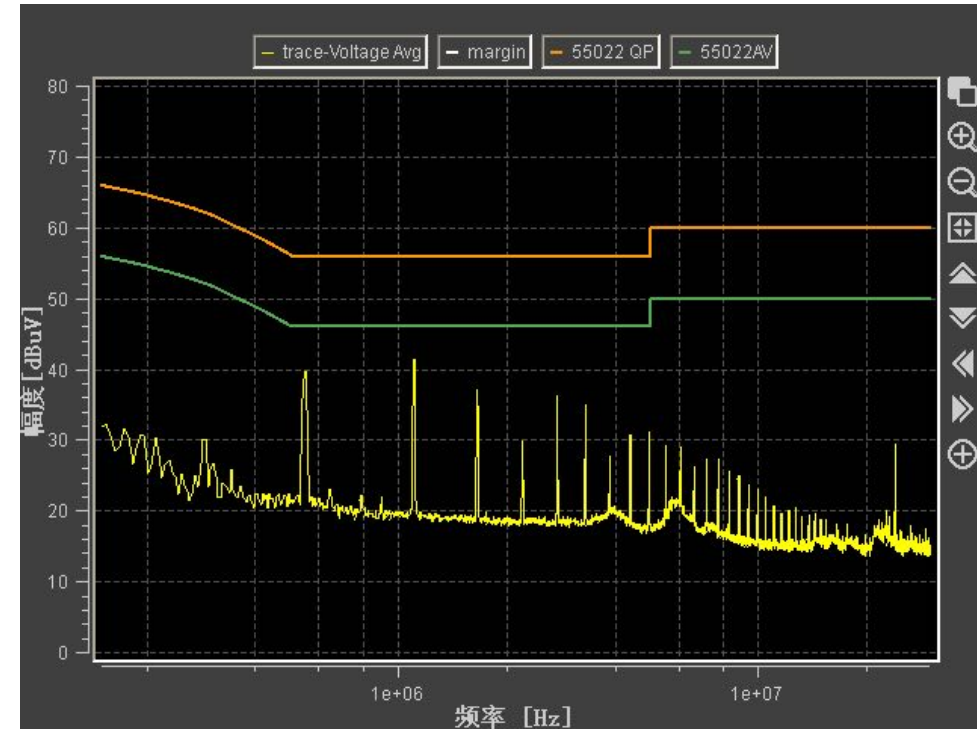
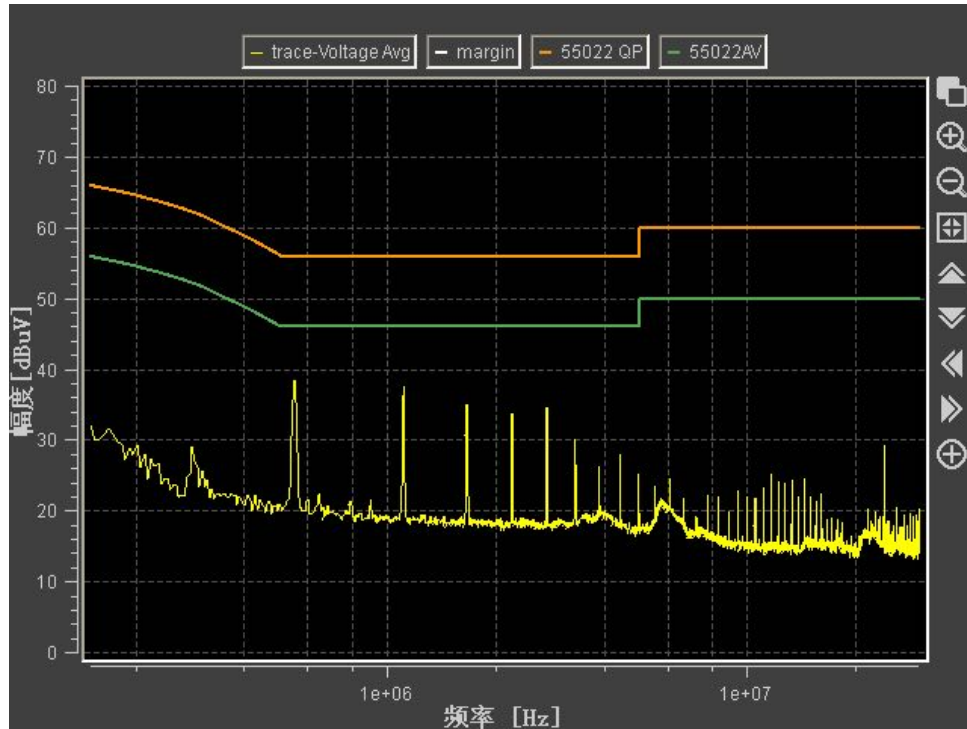
45 W Mu One: Efficiency





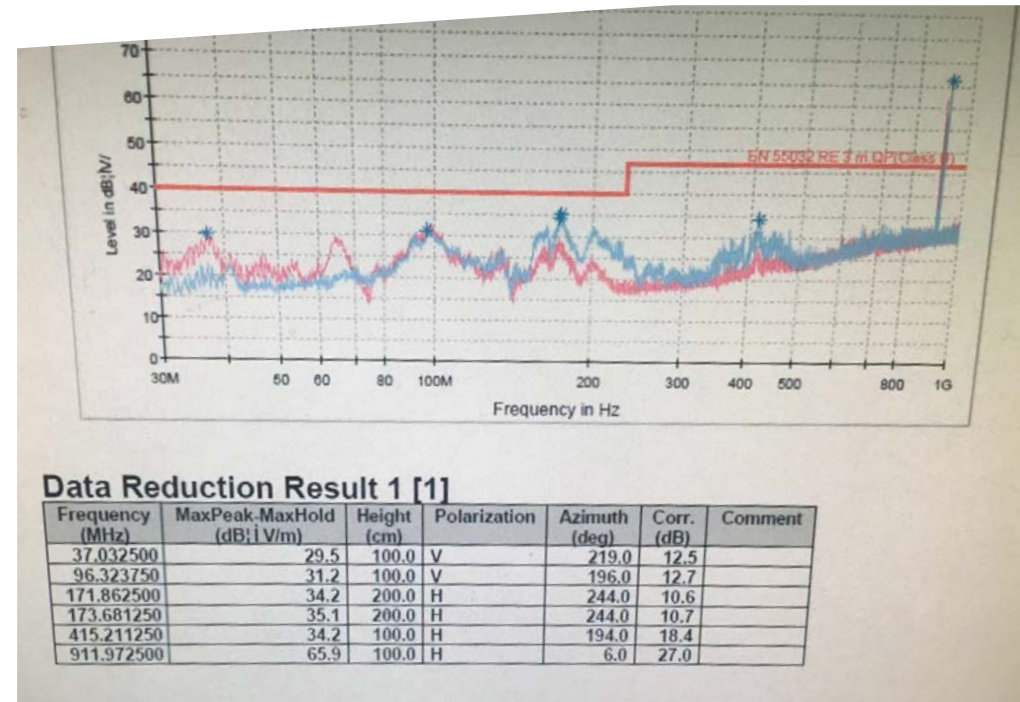
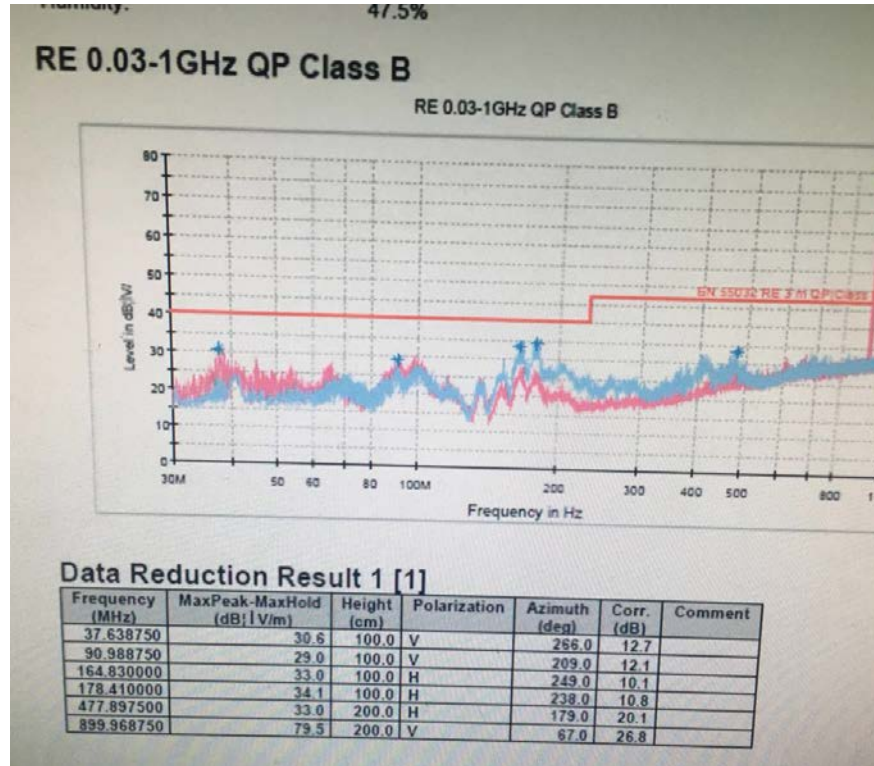
45W Mu One Conducted EMI

GaNFast™



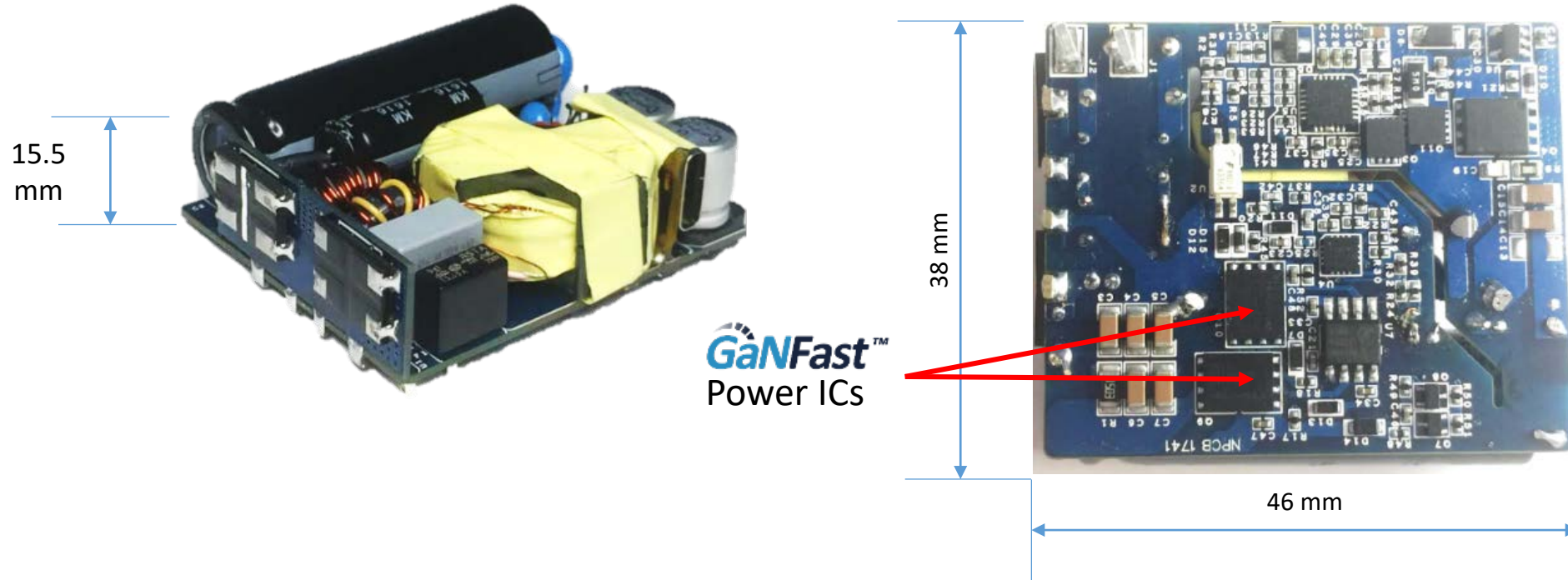


45W Mu One: Radiated EMI





World's Smallest 65 W USB-PD Adapter **GaNFast™**



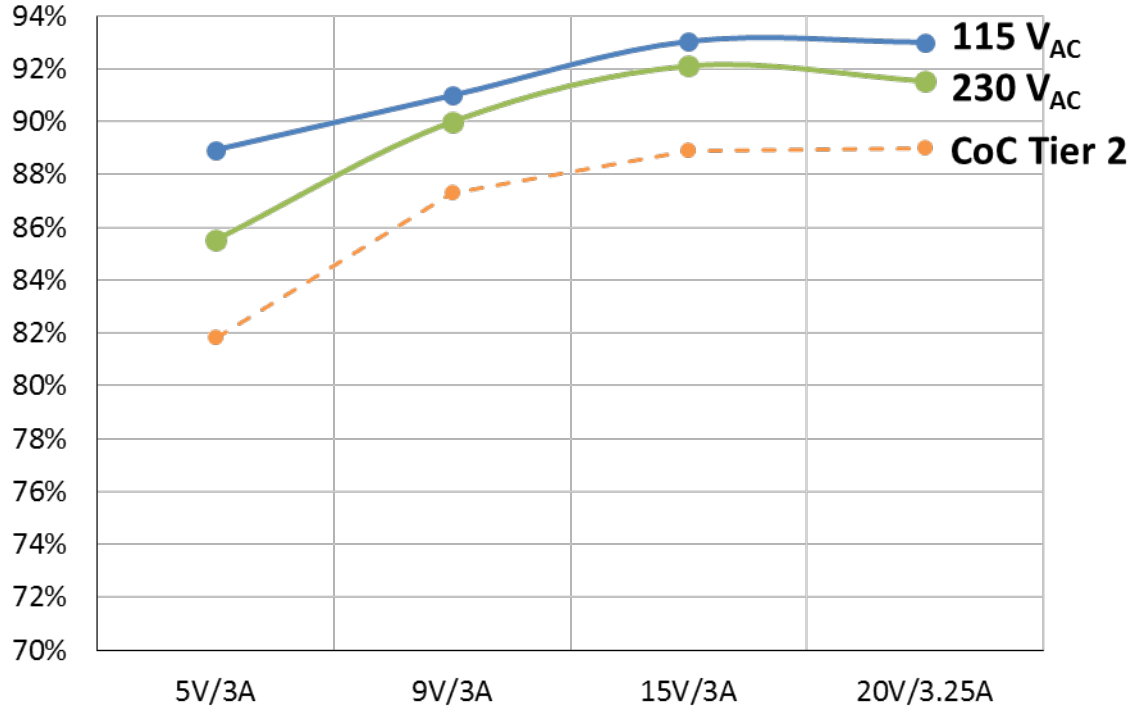
Power, Output	65 W USB-PD
Topology	ACF with UCC28780 and NV6115, NV6117 GaNFast Power ICs
Frequency	300 kHz
Size	27 cc (45 cc with case)
Density	2.4 W/cc (39 W/in ³) (1.5 W/cc (24 W/in ³) cased)
Efficiency	>93% peak, 92.8% at 90 V _{AC} , full load DoE Level VI, Euro CoC (EuP) Tier 2



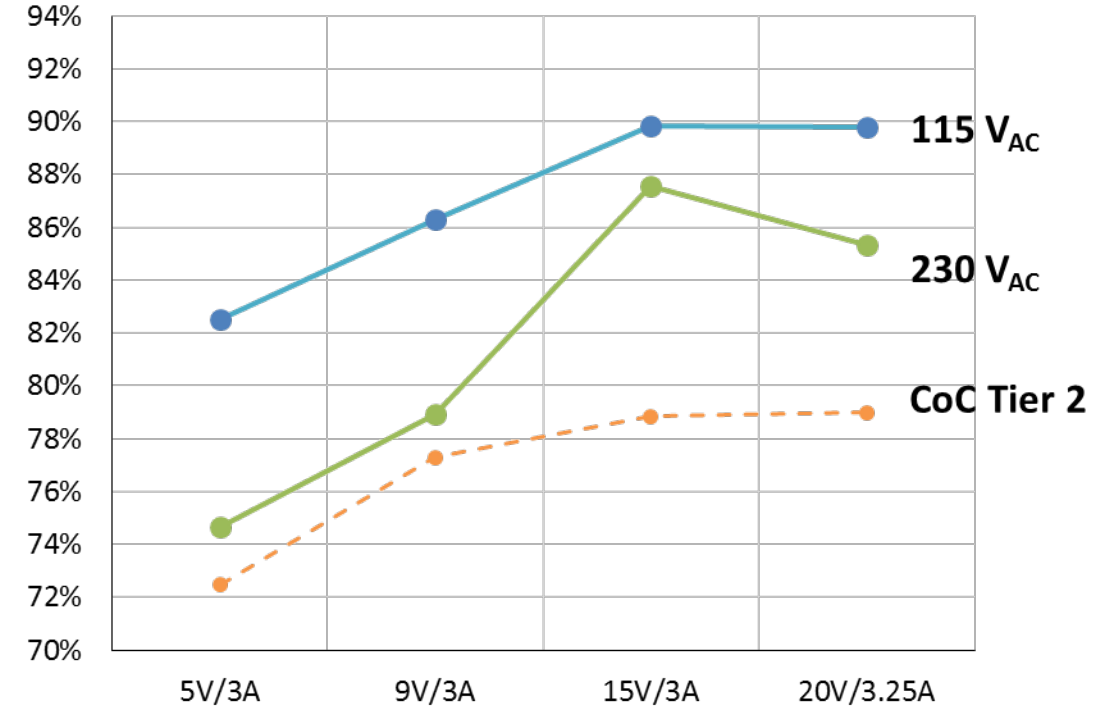
Highest Efficiency



4-Point Average Efficiency



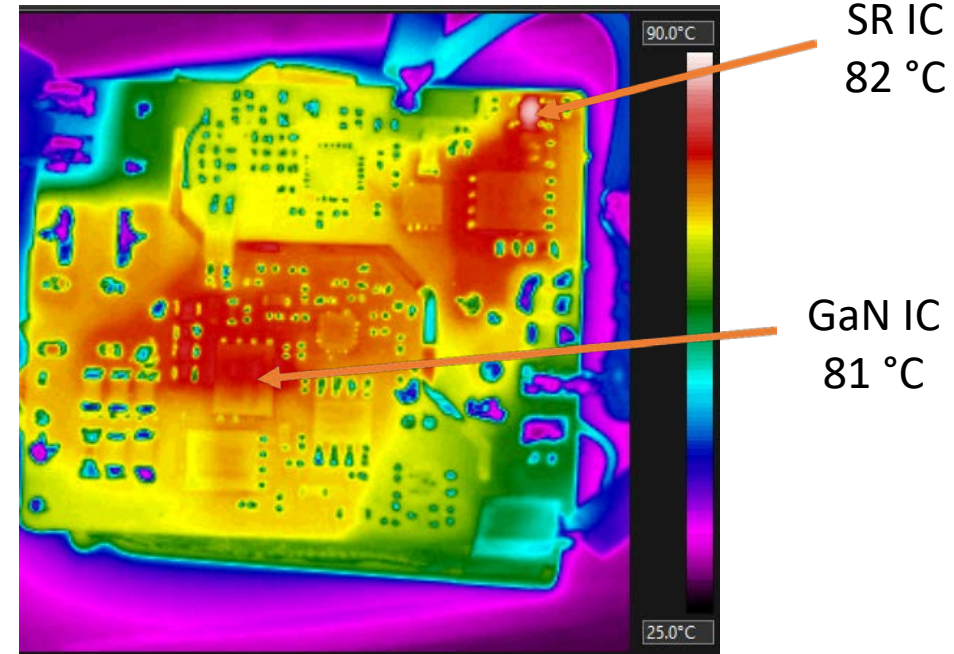
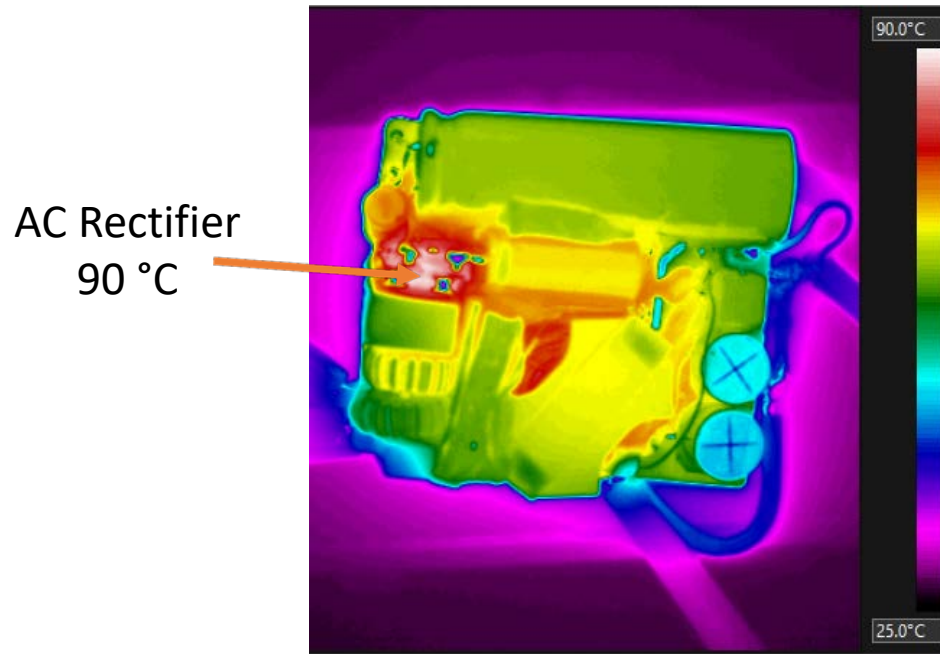
10% Load Efficiency



- Peak efficiency = 94.3% at 230 V_{AC}, full load (20V/3.25A)
- Lowest line efficiency = 93.4% at 90 V_{AC}, full load
- Standby: 25 mW at 115 V_{AC}, 40 mW at 230 V_{AC}
 - CoC Tier 2 spec is < 75mW, DoE Level VI spec <= 210 mW



Cool Performance

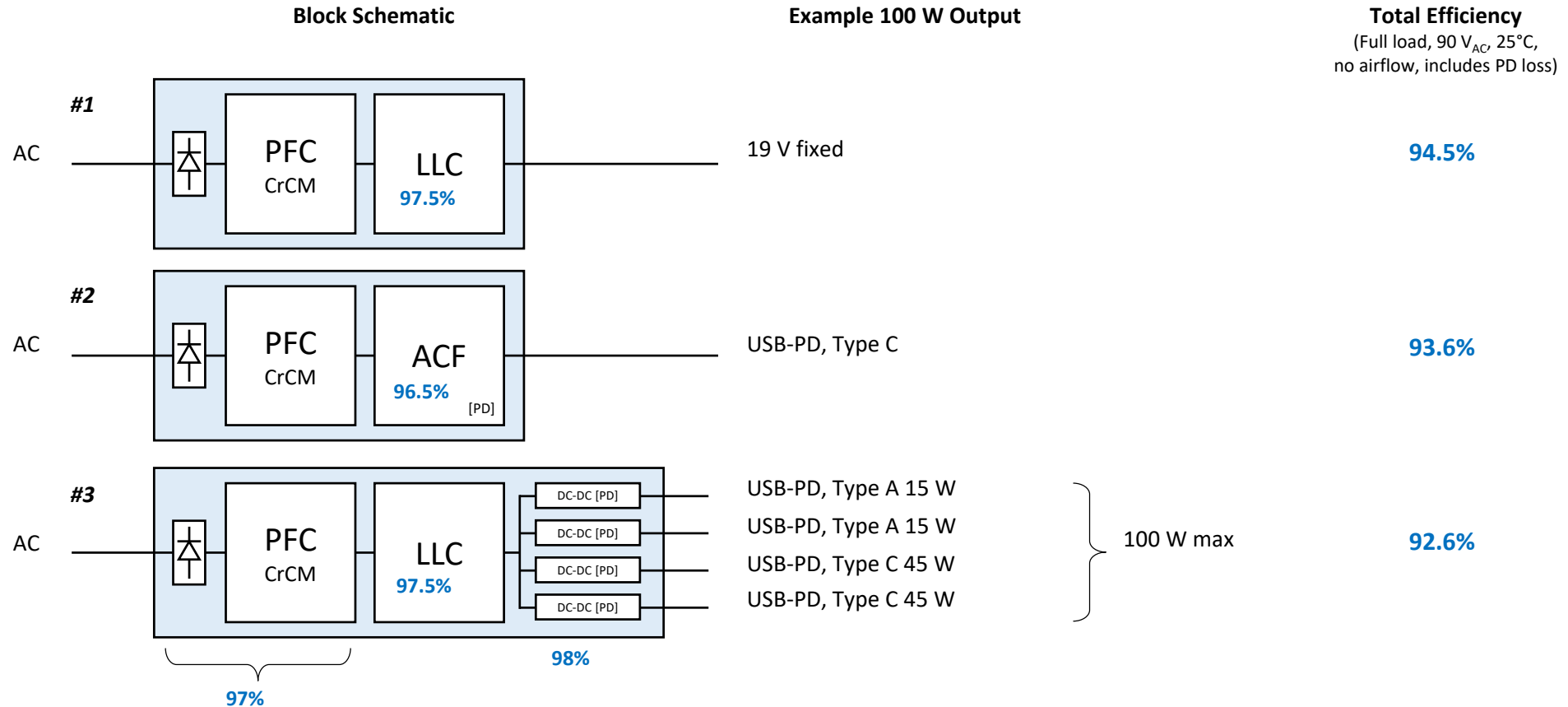


- Meets customer case specification of $\leq 50^{\circ}\text{C}$
- Conditions: 115V_{AC} , 20V_{DC} , 65W , 25°C ambient, no airflow, no heatsink



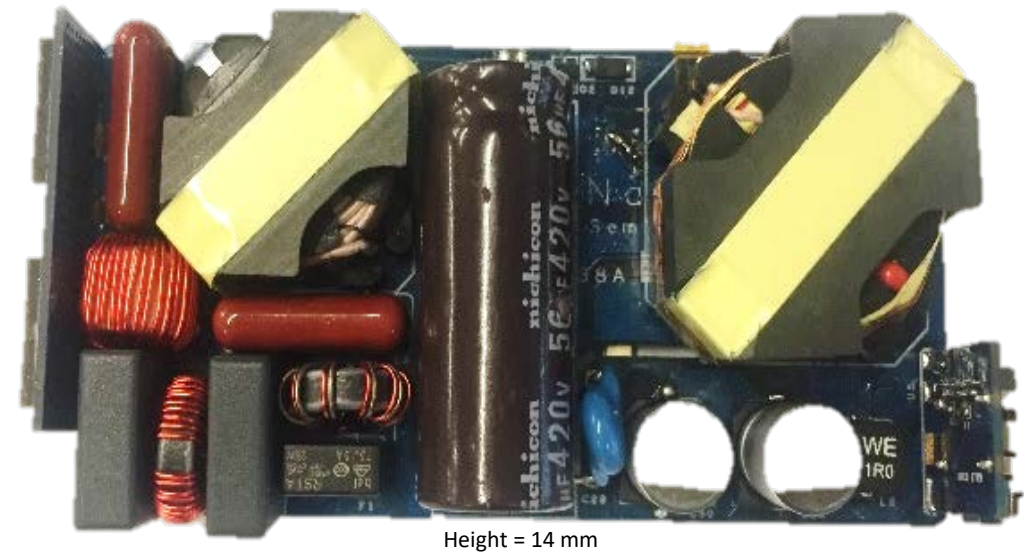
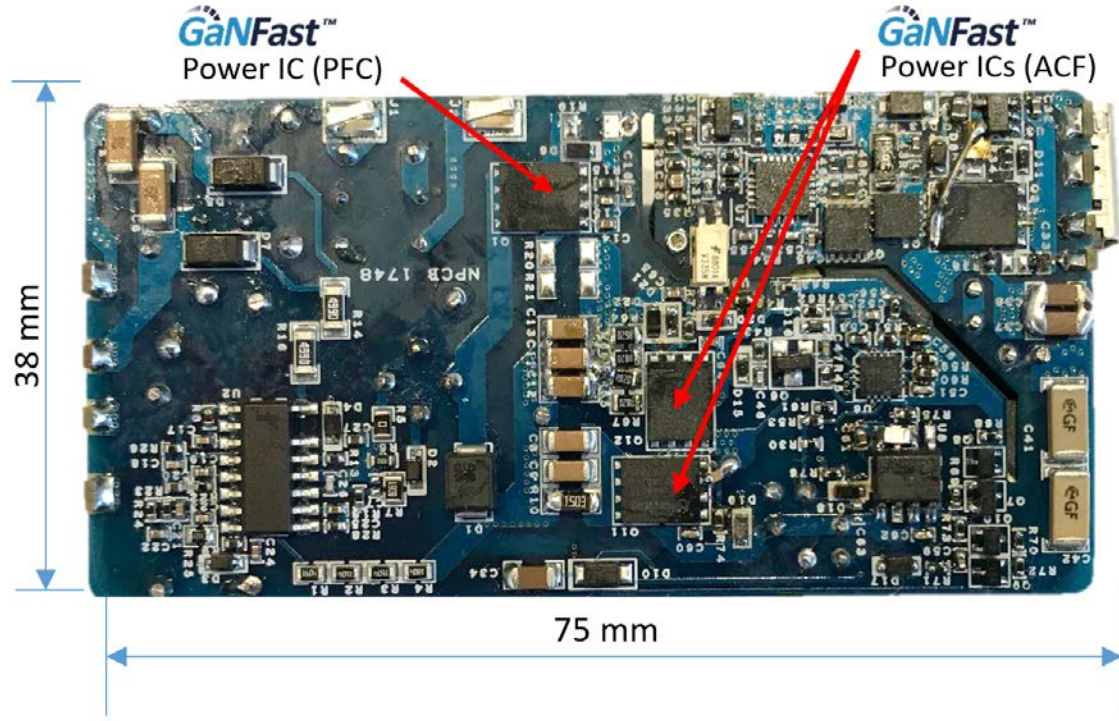
100W: Topology?

- Fixed or variable output?
 - LLC best for fixed output
 - ACF best for variable (PD) output





World's Smallest 100 W USB-PD



Power, Output	100 W USB-PD
Topology	CrCM PFC with NCP1615 and NV6115 GaNFast Power IC ACF with UCC28780 and NV6115, NV6117 GaNFast Power ICs
Frequency	PFC min. 200 kHz, ACF 300 kHz
Size	40 cc (65 cc with case)
Density	2.5 W/cc (41 W/in ³) (1.5 W/cc (25 W/in ³) cased)
Efficiency	>93.7% peak, 92.1% (target >93%) at 90 V _{AC} , full load, DoE Level VI, Euro CoC (EuP) Tier 2

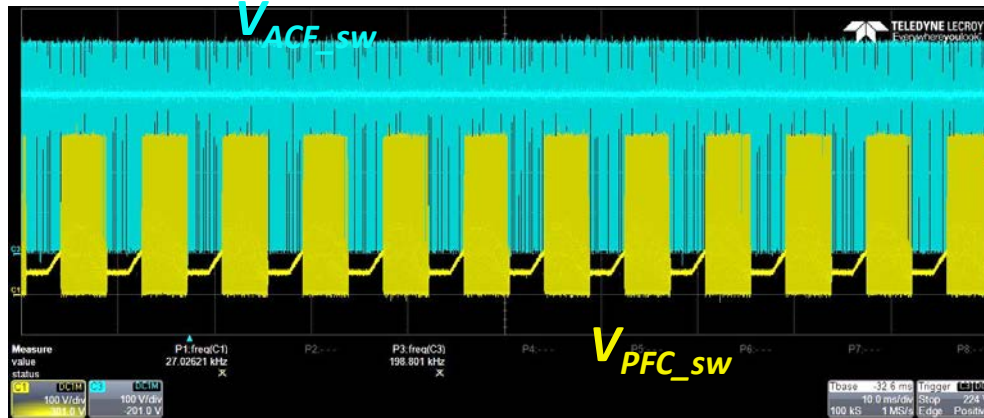


100 W USB-PD



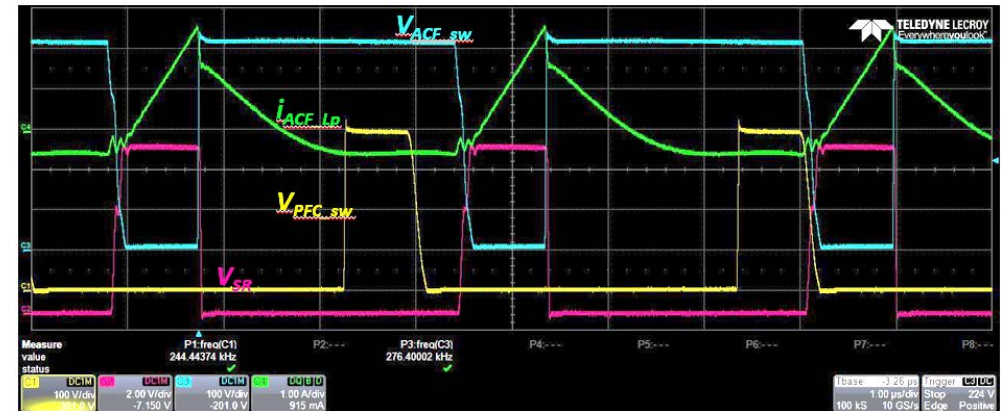
Light Load (20 V, 500 mA)

10 ms/div



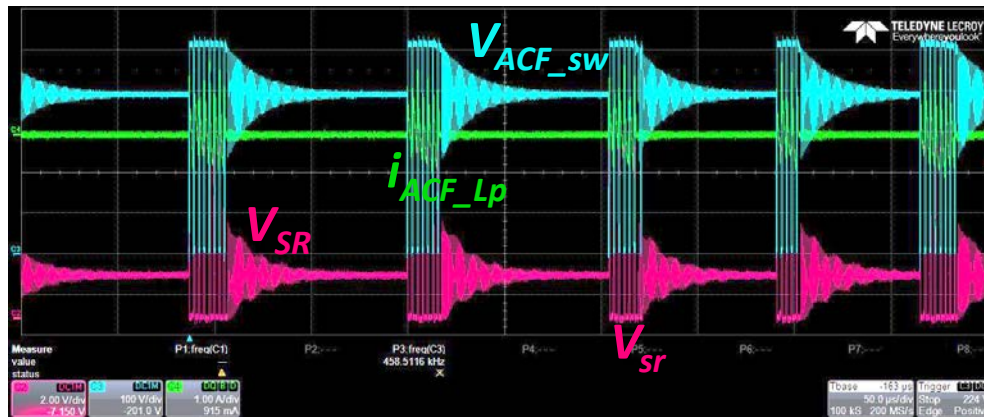
Heavy Load (20 V, 4.8 A)

1 us/div



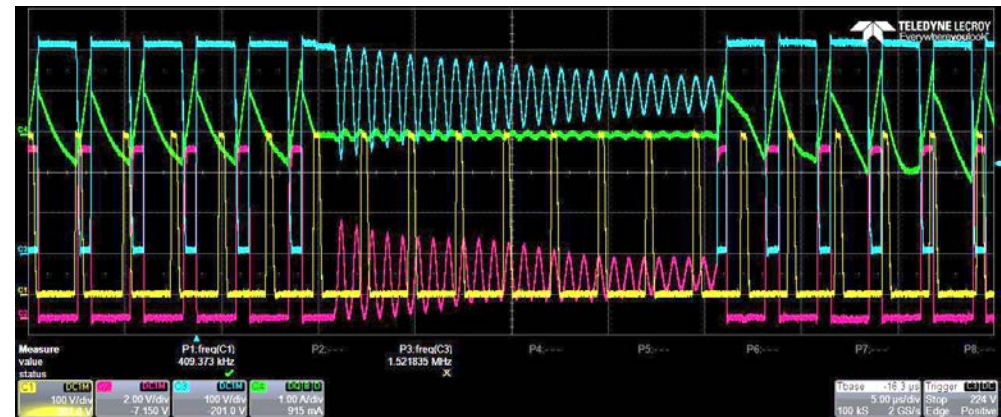
Light Load (20 V, 500 mA, zoom)

50 us/div



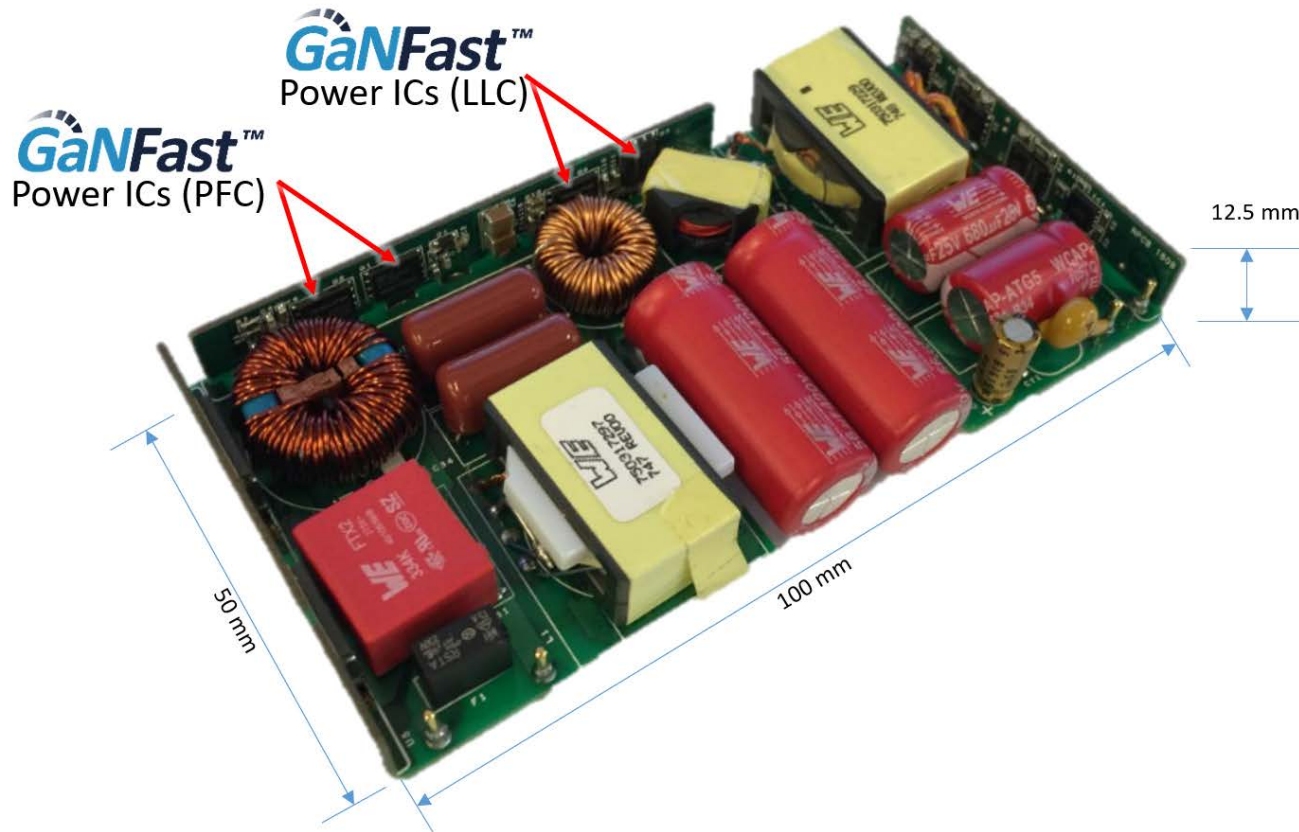
Half Load (20V, 2.5A)

5 us/div





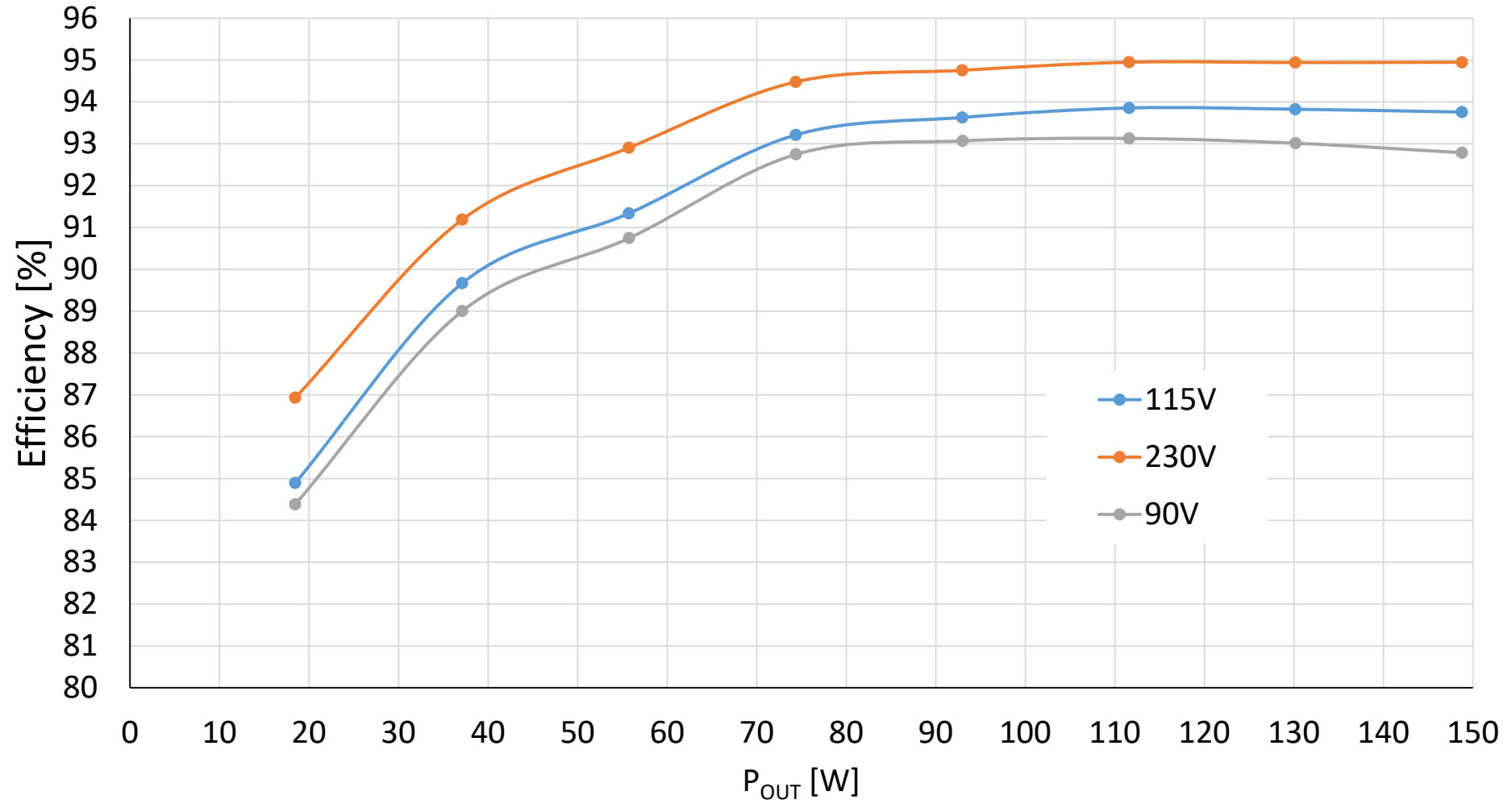
150 W, 19 V: 200/500 kHz



Power, Output	150 W, 19 V
Topology	CrCM PFC NCP1615 & LLC NCP13992AB with NV6115 GaNFast Power ICs
Frequency	PFC min. 200 kHz, LLC typ. 500 kHz
Size	63 cc (101 cc with case)
Density	2.4 W/cc (39 W/in ³) 1.5 W/cc (24 W/in ³) cased
Efficiency	95% peak, 93% at 90 V _{AC} , full load DoE Level VI, Euro CoC (EuP) Tier 2

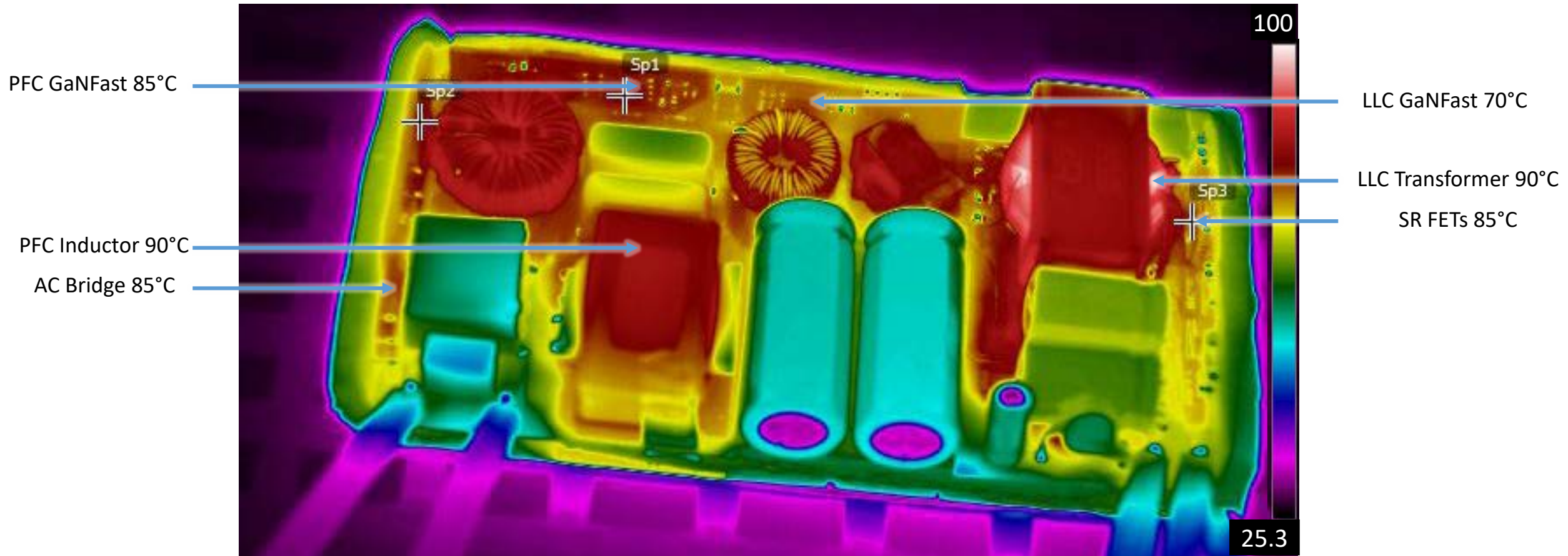


150 W Highest Efficiency





150 W Cool Operation



90 V_{AC}, 150 W, 25 °C, uncased, no airflow



Let's go **GaNFast™**